

# Model-Based Testing of Real-time Systems

using **UPPAAL COVER** and



# Uppaal's Branches for Testing

- Uppaal's branches for testing:
  - Uppaal-TRON
  - Uppaal-Cover

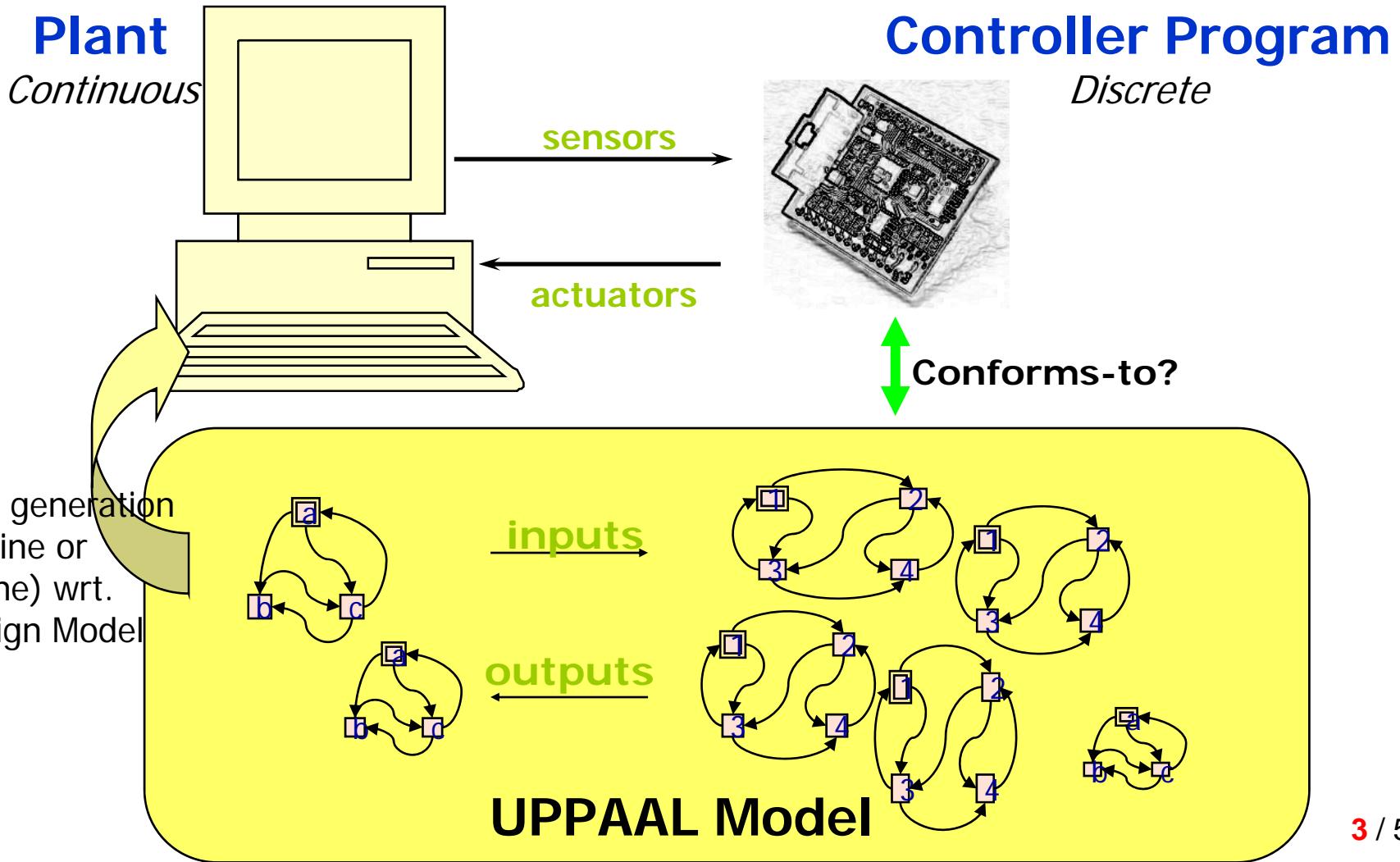


(Off-line testing)



(On-line testing)

# Real-time Model-Based Testing



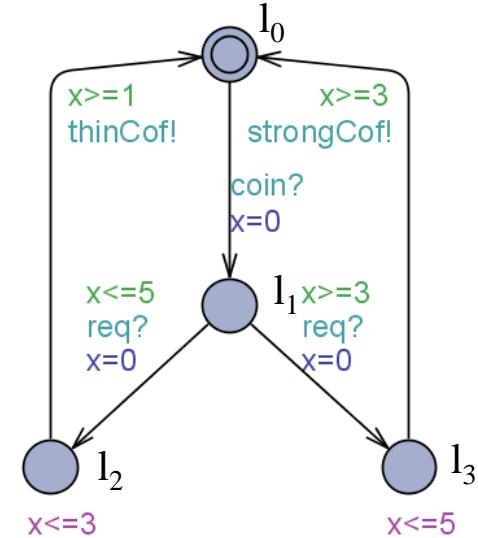
# Timed System Testing

- Model:
  - Timed Input-Output Labelled Transition System (**Timed IOLTS**)
- Conformance relation:
  - Timed Input-Output Conformance (**Timed ioco**)

# Timed IOLTS by Example

- Given a timed automaton:
  - location:  $\{l_0, l_1, l_2, l_3\}$
  - actions:
    - $\{\text{coin?}, \text{req?}\}$  --- input actions
    - $\{\text{thinCof!}, \text{strongCof!}\}$  --- output actions
  - clock:  $\{x\}$

- Semantic state:
  - e.g.:  $(l_0, x=0), (l_0, x=2), (l_1, x=4)$
- Semantic transition:
  - e.g.:  $(l_0, x=0) \xrightarrow{\text{delay}(2)} (l_0, x=2),$   
 $(l_0, x=2) \xrightarrow{\text{coin?}} (l_1, x=0),$

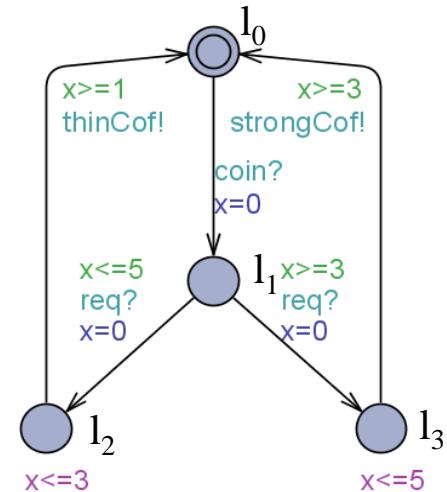


Such a transition system is a **timed IOLTS**

- as semantic interpretation of TA
- typically infinite transition systems (because clocks are real variables)

# Timed Conformance: tioco

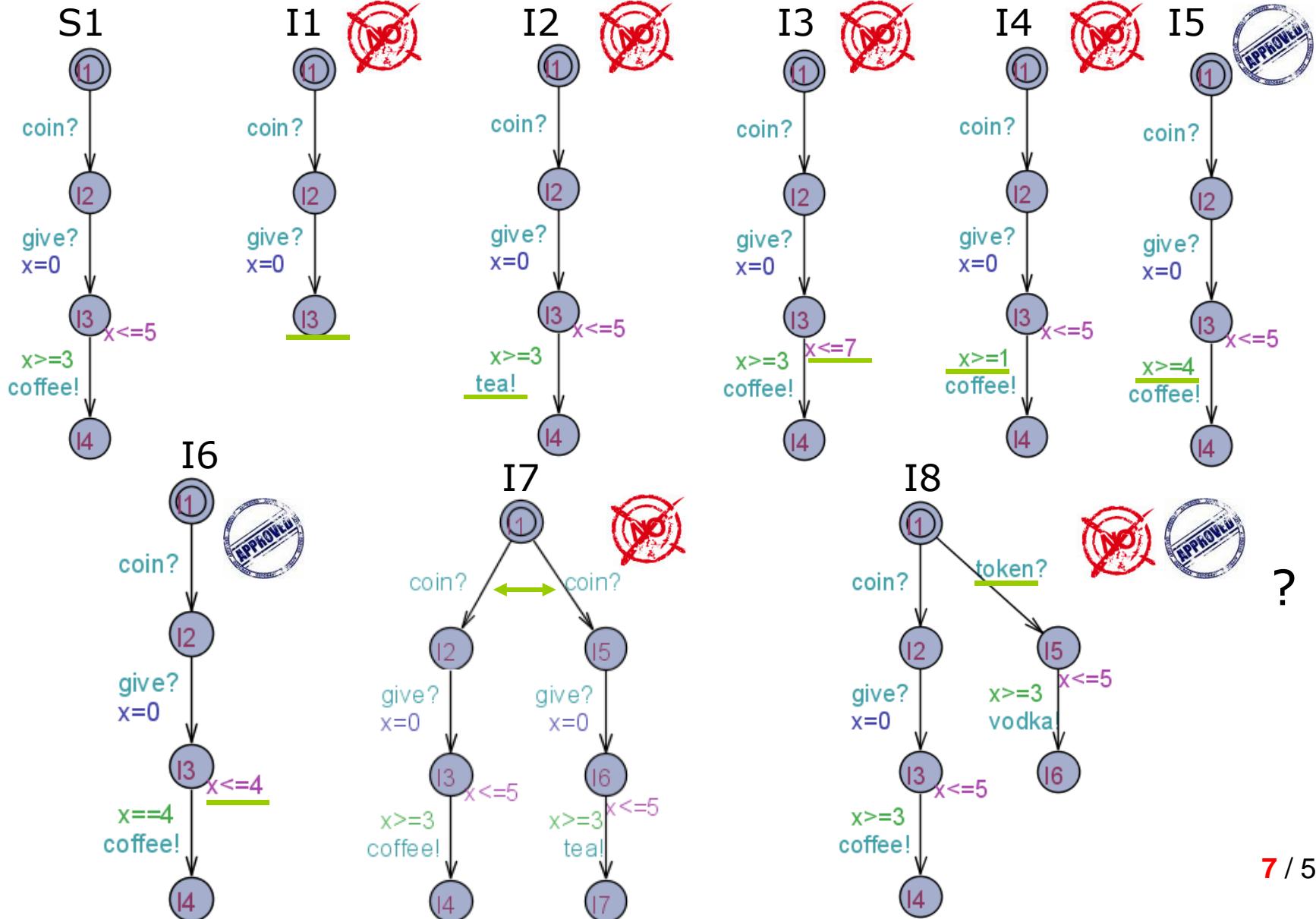
- Derived from Tretman's **ioco**
- Let  $I, S$  be two timed IOLTS's,  $P$  a set of states
  - $TTr(P)$ : the set of **timed traces** from a state in  $P$ 
    - e.g.:  $\sigma = \text{coin?}.5.\text{req?}.2.\text{thinCoffee!}.9.\text{coin?}$
  - $Out(P \text{ after } \sigma) = \text{possible outputs and delays after } \sigma$ 
    - e.g.  $out(\{l_2, x=1\}) = \{\text{thinCoffee}, 0\dots 2\}$



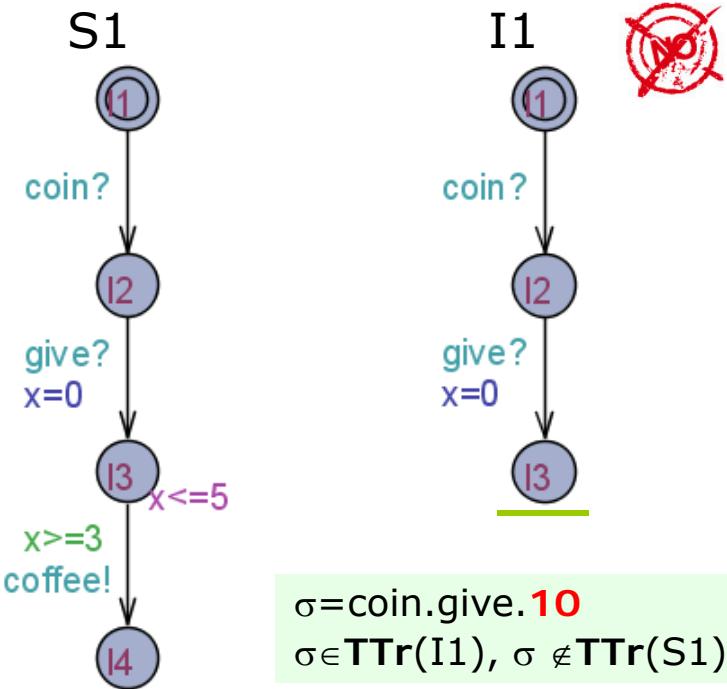
- $I \text{ tioco } S \stackrel{\text{def}}{=} \{ \sigma \in TTr(S) : Out(I \text{ after } \sigma) \subseteq Out(S \text{ after } \sigma), \text{ or }$
- $TTr(i_0) \subseteq TTr(s_0)$ , where  $i_0$  and  $s_0$  are the initial states of  $I$  and  $S$  respectively

- Intuition
  - IUT can accept all inputs for SPEC (and perhaps some other inputs)
  - if IUT ever produces an output as required by SPEC, it should be produced **in time**
  - but IUT is **not allowed** to produce any **illegal** output (w.r.t. SPEC)

# Does $I_n$ Conform-to $S_1$ ?



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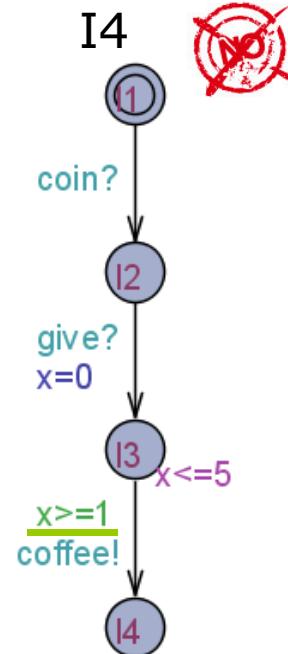
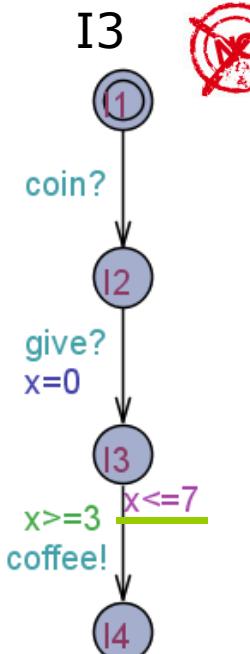
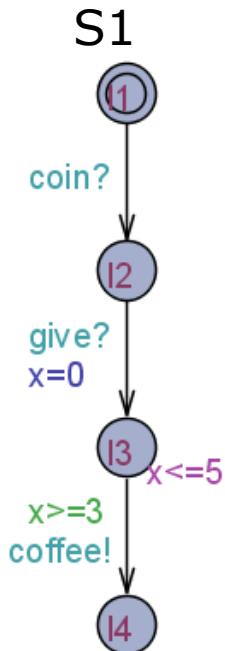
$\sigma = \text{coin.give.10}$   
 $\sigma \in \text{TTr}(I_1), \sigma \notin \text{TTr}(S_1)$

**out( $I_1$  after coin.give.3) = {0... $\infty$ }**

$\not\subseteq$

**out( $S_1$  after coin.give.3) = {coffee, 0...2}**

# Does $I_n$ Conform-to $S_1$ ?



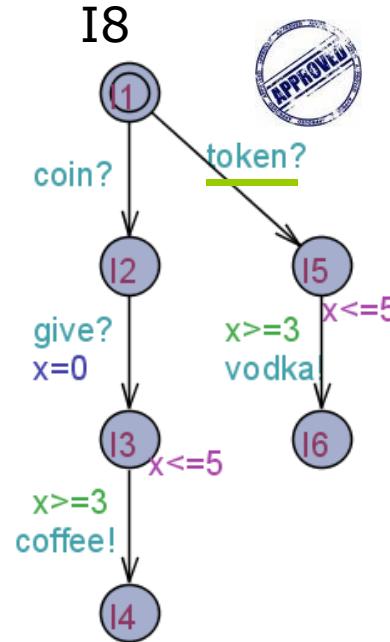
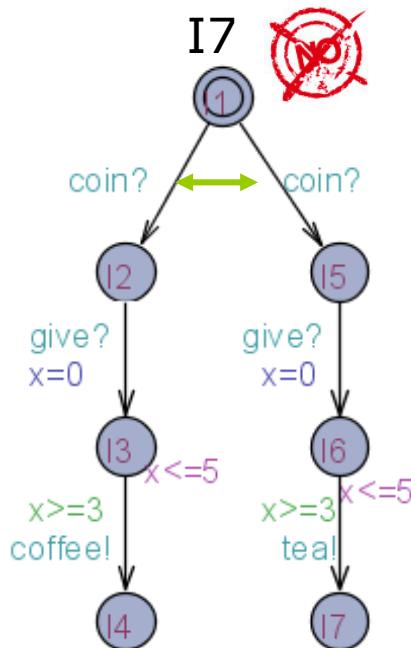
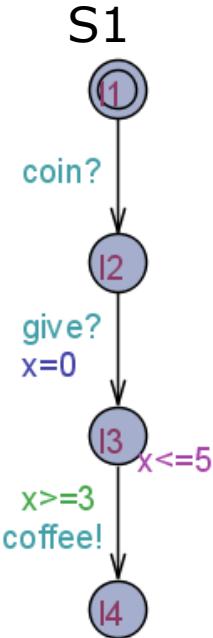
$\sigma = \text{coin.give.7.coffee}$   
 $\sigma \in \text{TTr}(I_3), \sigma \notin \text{TTr}(S_1)$

**out**( $I_3$  after coin.give.7) = {coffee, 0}  
 $\not\subset$   
**out**( $S_1$  after coin.give.7) = {}

$\sigma = \text{coin.give.1.coffee}$   
 $\sigma \in \text{TTr}(I_4), \sigma \notin \text{TTr}(S_1)$

**out**( $I_4$  after coin.give.1) = {coffee, 0...4}  
 $\not\subset$   
**out**( $S_1$  after coin.give.1) = {0...4}

# Does $I_n$ Conform-to $S_1$ ?



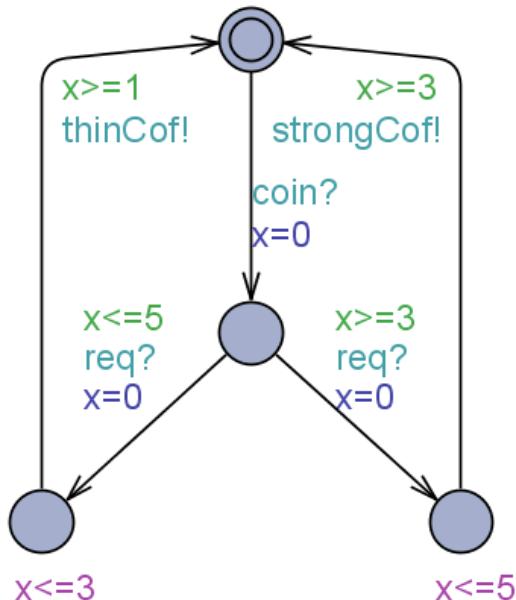
$\sigma = \text{coin.give.5.tea}$   
 $\sigma \in \text{TTr}(I_7), \sigma \notin \text{TTr}(S_1)$

**out( $I_7$  after coin.give.5) = {tea, coffee, 0}**  
 $\not\subset$   
**out( $S_1$  after coin.give.5) = {coffee, 0}**

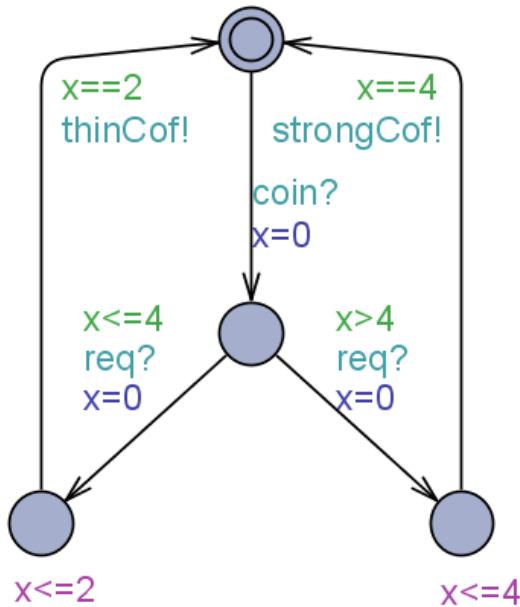
$\sigma = \text{token.5.vodka}$   
 $\sigma \in \text{TTr}(I_8), \sigma \notin \text{TTr}(S_1)$   
**But**  $\sigma$  was not specified in  $S_1$

# Now, Back to Timed Coffee Machine

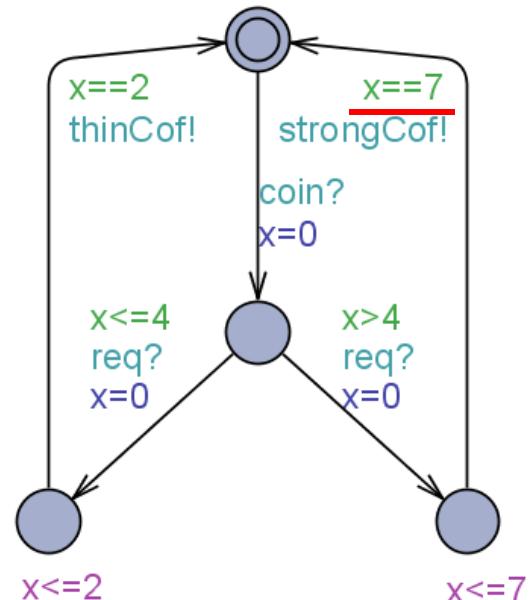
Specification



Implementation 1



Implementation 2



Example Traces

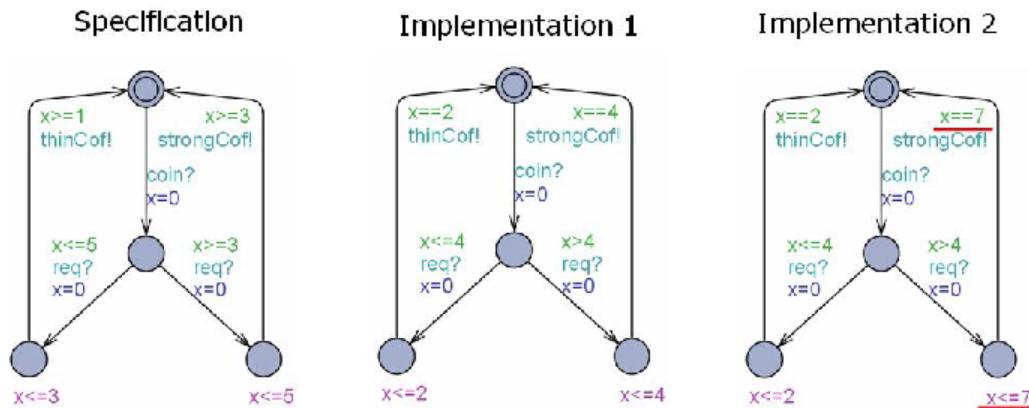
- c?.2.r?.2.weakC
- c?.5.r?.4.strongC

I1 **rt-ioco** S

- c?.2.r?.2.weakC
- c?.5.r?.7

I2 **rt*oco*** S 11 / 59

# Essence of “Timed ioco”?

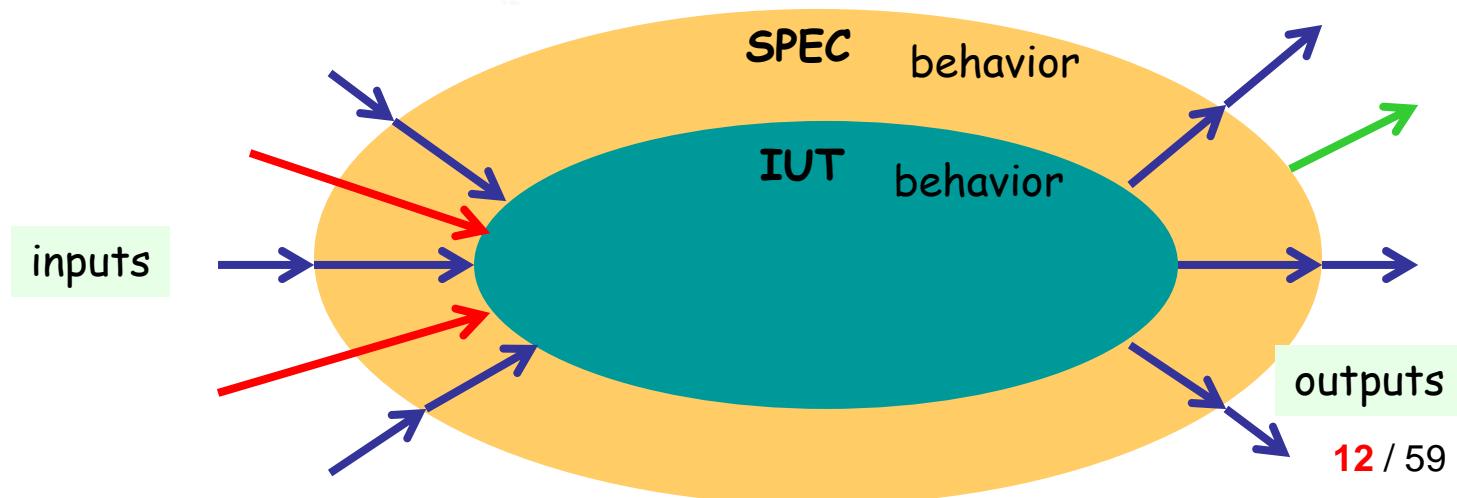


## Example Traces

- c?.2.r?.2.weakC
- c?.5.r?.4.strongC
- c?.2.r?.2.weakC
- c?.5.r?.7

I1 **rt-ioco** S

I2 **rt*/*ioco** S



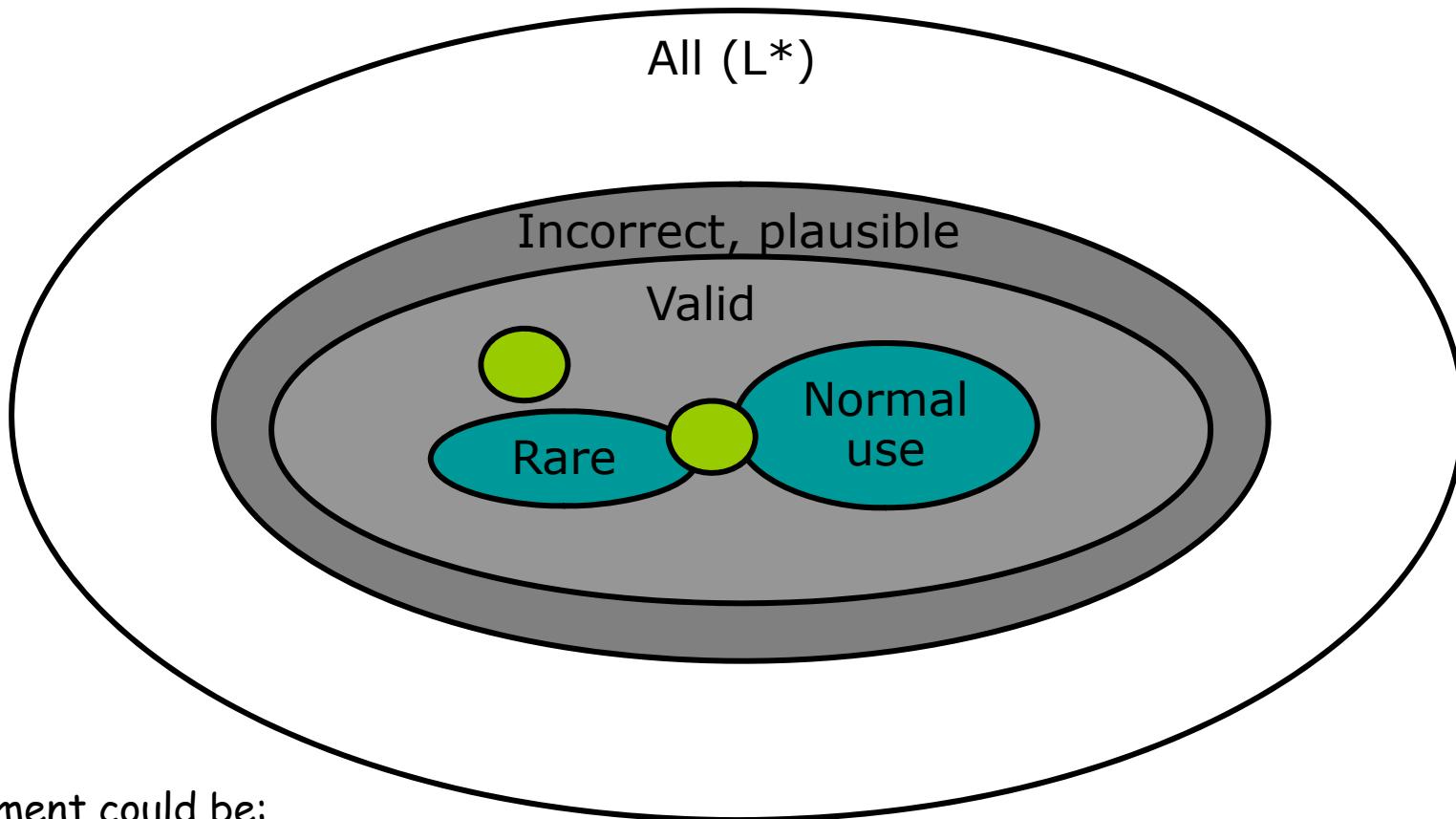
# Explicit Environment Modelling

Recall that in "ioco" conformance...

- $I \text{ tioco } S \stackrel{\text{def}}{=} \{ \sigma \in TTr(S) : \text{Out}(I \text{ after } \sigma) \subseteq \text{Out}(S \text{ after } \sigma), \text{ or}$ 
  - $TTr(i_0) \subseteq TTr(s_0)$ , where  $i_0$  and  $s_0$  are the initial states of  $I$  and  $S$  respectively

- Note that:
  - $TTr(S)$  is a **very big** (infinite) set
  - We are usually interested in only a small portion of the behavior
- A solution:
  - To explicitly model the environment that the IUT will be operated in

# The Environment "Universe"

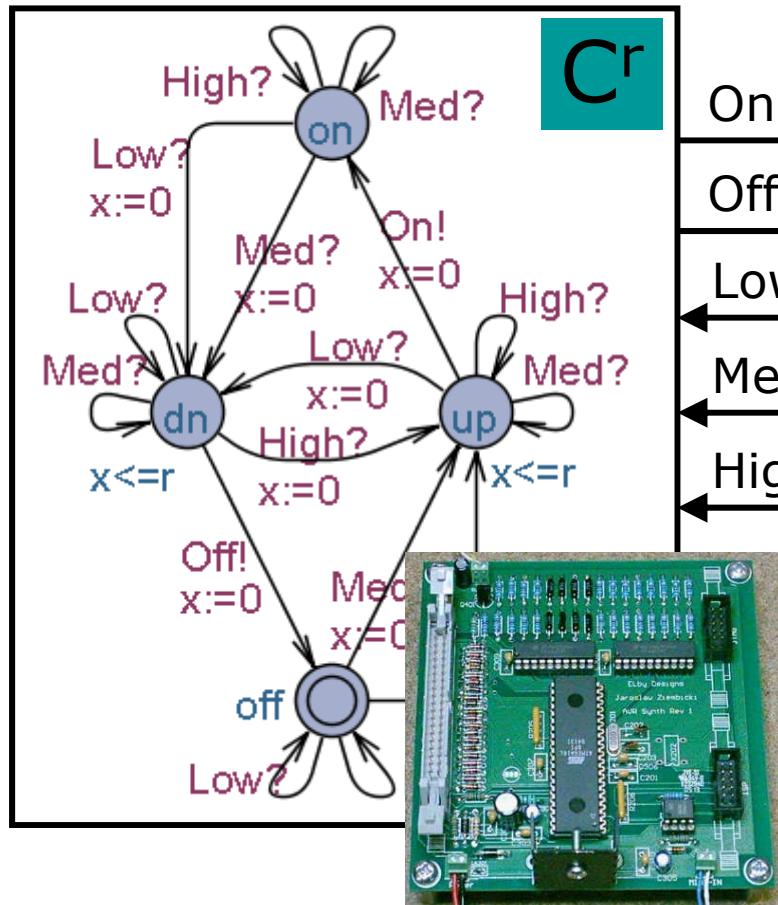


environment could be:

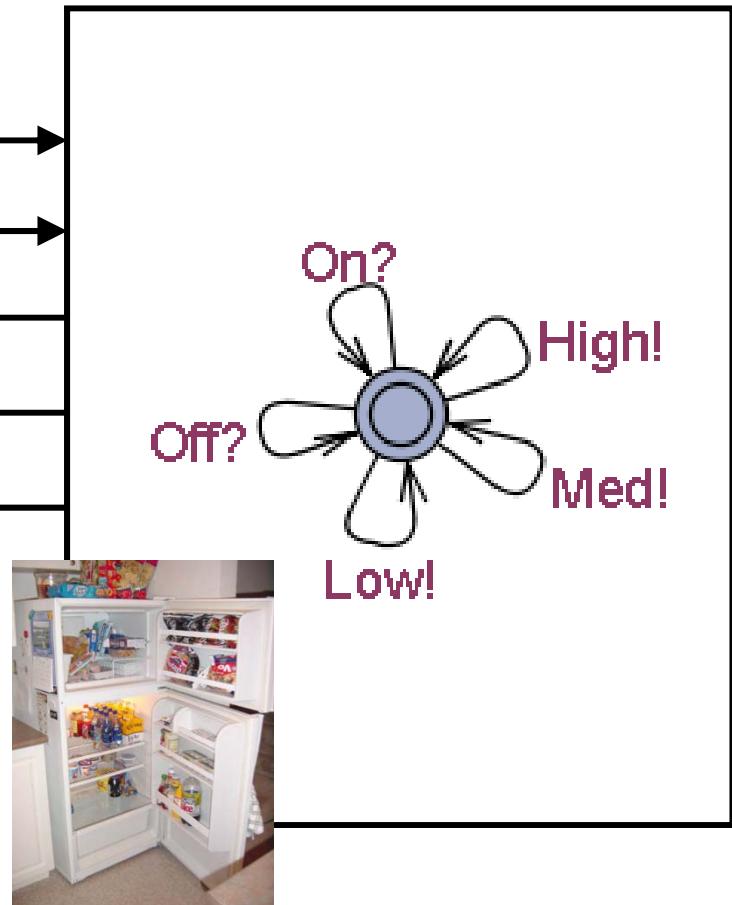
- Other external systems (Dedicate / open protocols)
- Other internal systems (eg powersupply, radio)
- Human Users
- Physical Plant via sensors / actuators

# Sample Cooling Controller

IUT-model



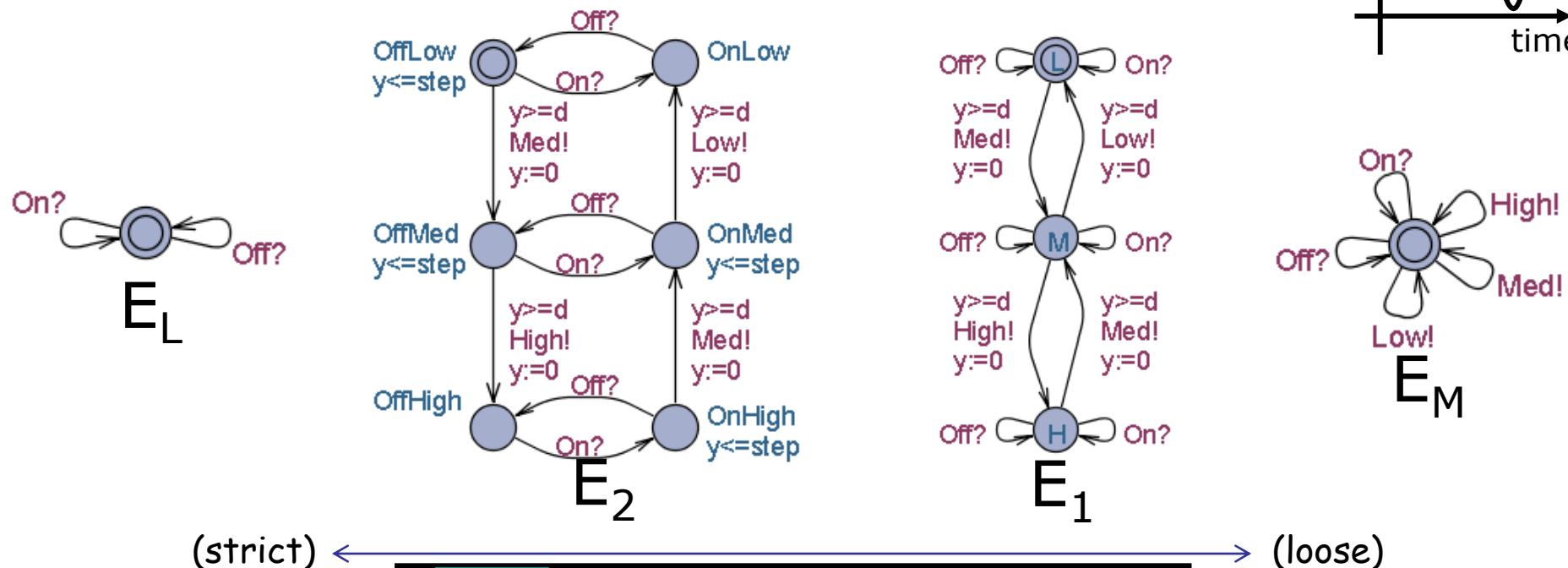
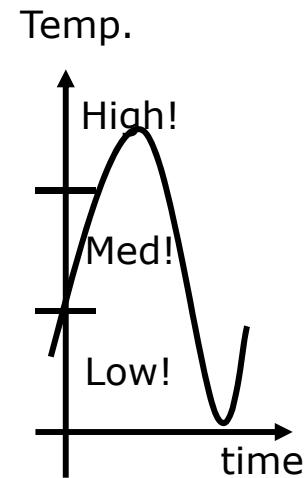
Env-model



- When  $T$  is high (low) switch on (off) cooling within  $r$  secs.
- When  $T$  is medium cooling may be either on or off (impl. freedom)

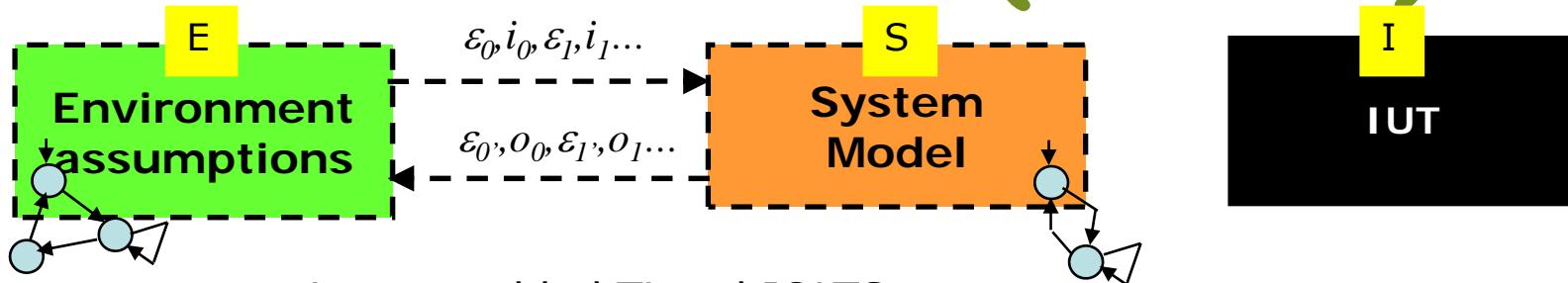
# Environment Modelling

- $E_M$  Any action possible at any time
- $E_1$  Only **realistic** temperature variations
- $E_2$  Temperature never increases when cooling
- $E_L$  No inputs (completely passive)



$$E_L \subseteq E_2 \subseteq E_1 \subseteq E_M$$

# Relativized Timed Input-Output Conformance (rt-ioco)



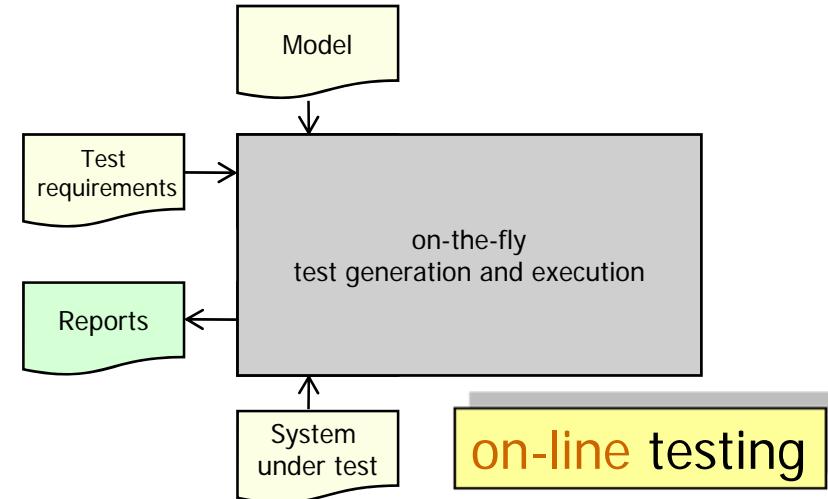
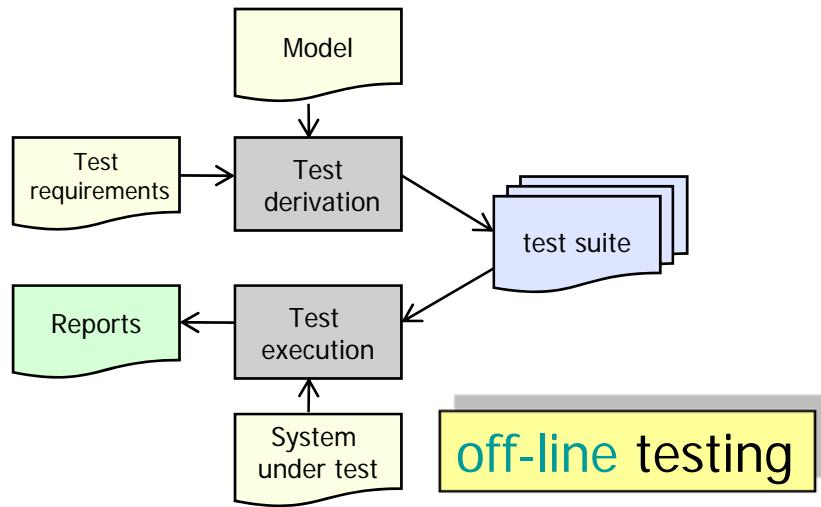
- $E, S, I$  are input-enabled Timed IOLTS
- Let  $P$  be a set of states
- $\text{TTr}(P)$ : the set of *timed traces* from states in  $P$
- $P$  after  $\sigma$  = the set of states reachable after timed trace  $\sigma$
- $\text{Out}(P)$  = possible outputs and delays from states in  $P$

- $I \text{ rt-ioco}_E S =_{\text{def}} \forall \sigma \in \text{TTr}(E): \text{Out}((E,I) \text{ after } \sigma) \subseteq \text{Out}((E,S) \text{ after } \sigma)$   
or
- $I \text{ rt-ioco}_E S$  iff  $\text{TTr}(I) \cap \text{TTr}(E) \subseteq \text{TTr}(S) \cap \text{TTr}(E)$  // *input enabled*

- Intuition: for all assumed environment behaviors, the IUT
  - never produces illegal output, and
  - if ever produces required output, then produces it in time

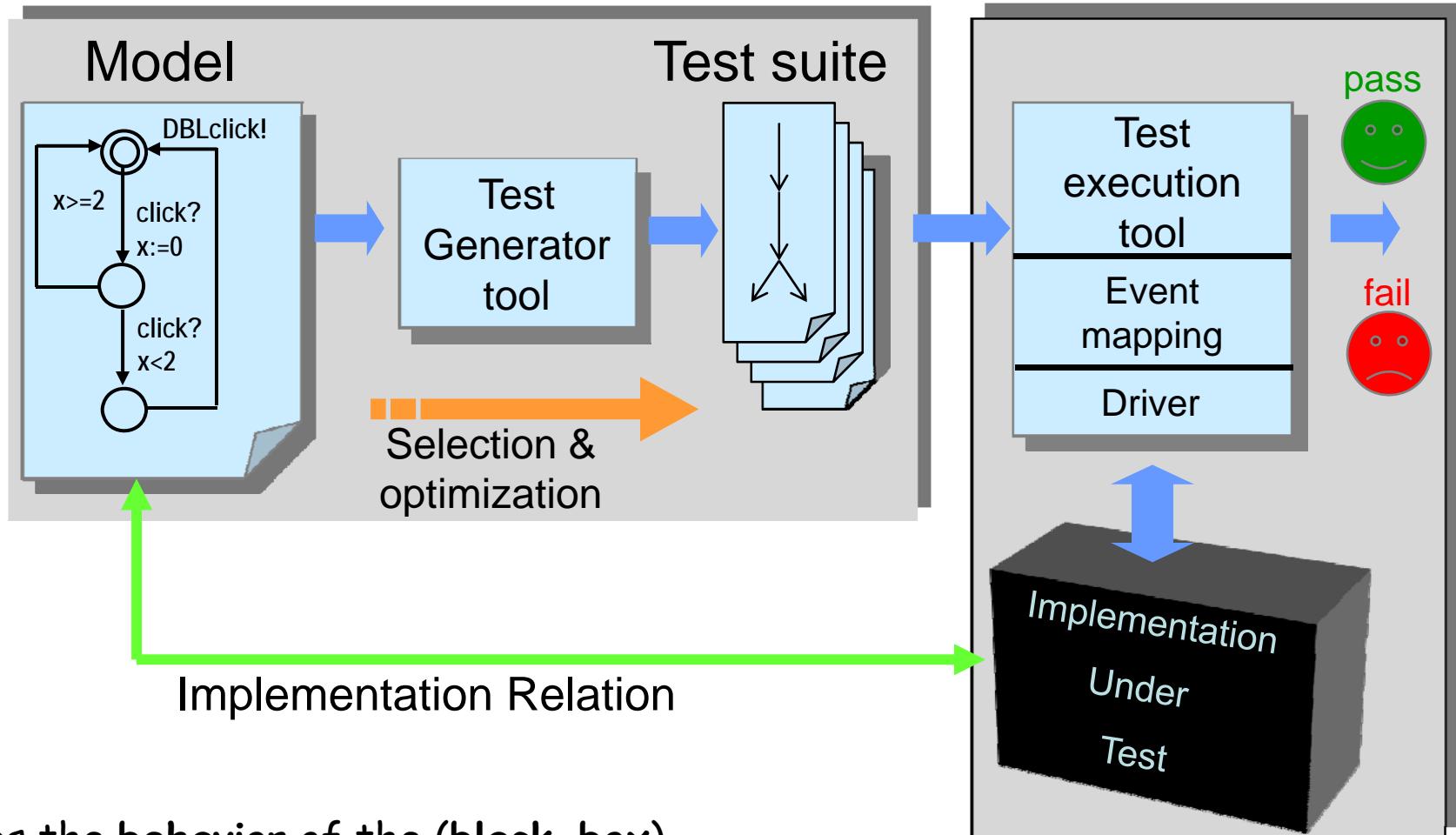
See also [Larsen 04 FATES]

# Off-line and On-line Testing



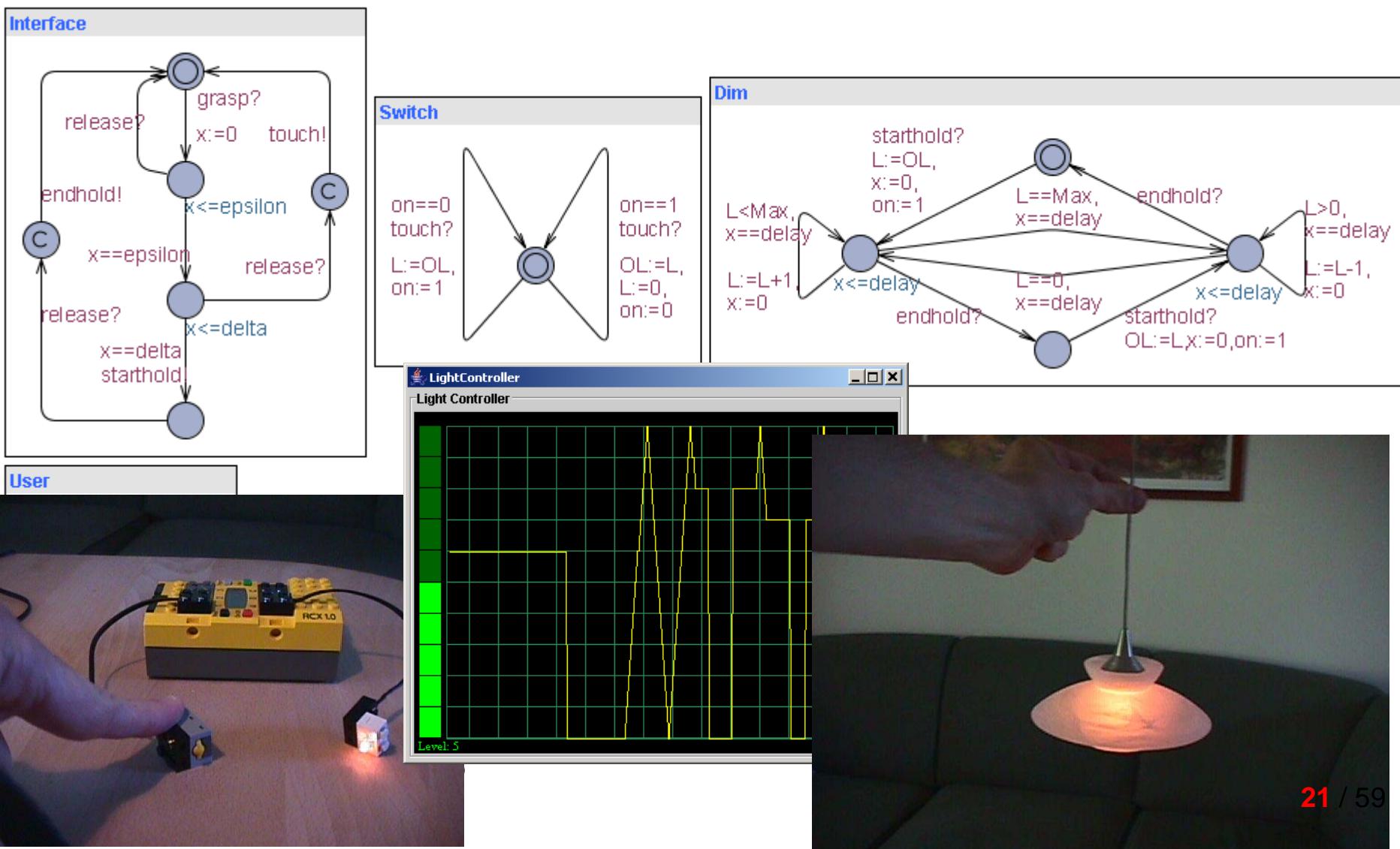
# Model-Based Off-line Testing of Timed Systems

# Automated Model-Based Off-line Conformance testing

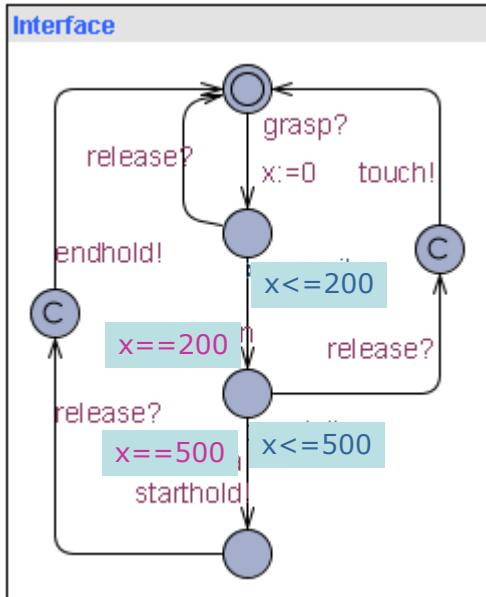


Does the **behavior** of the (black-box) implementation *comply* to that of the specification?

# Touch-sensitive Light Controller



# Timed Tests

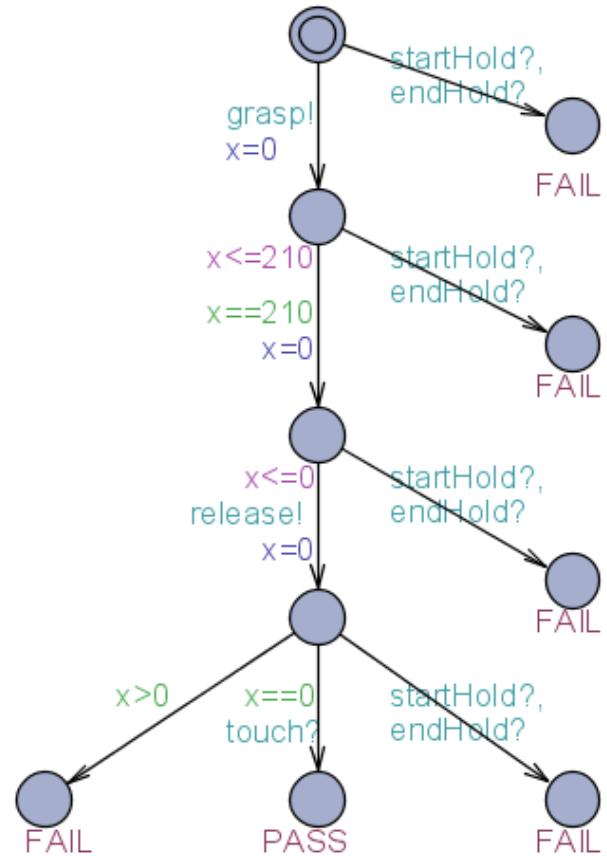


**EXAMPLE** test cases for **Interface**

0 · grasp! · 210 · release! · touch? · **PASS**

0 · grasp! · 317 · release! · touch? · 2½ · grasp! · 220 · release! · touch? · **PASS**

1000 · grasp! · 517 · starthold? · 100 · release! · endhold? · **PASS**

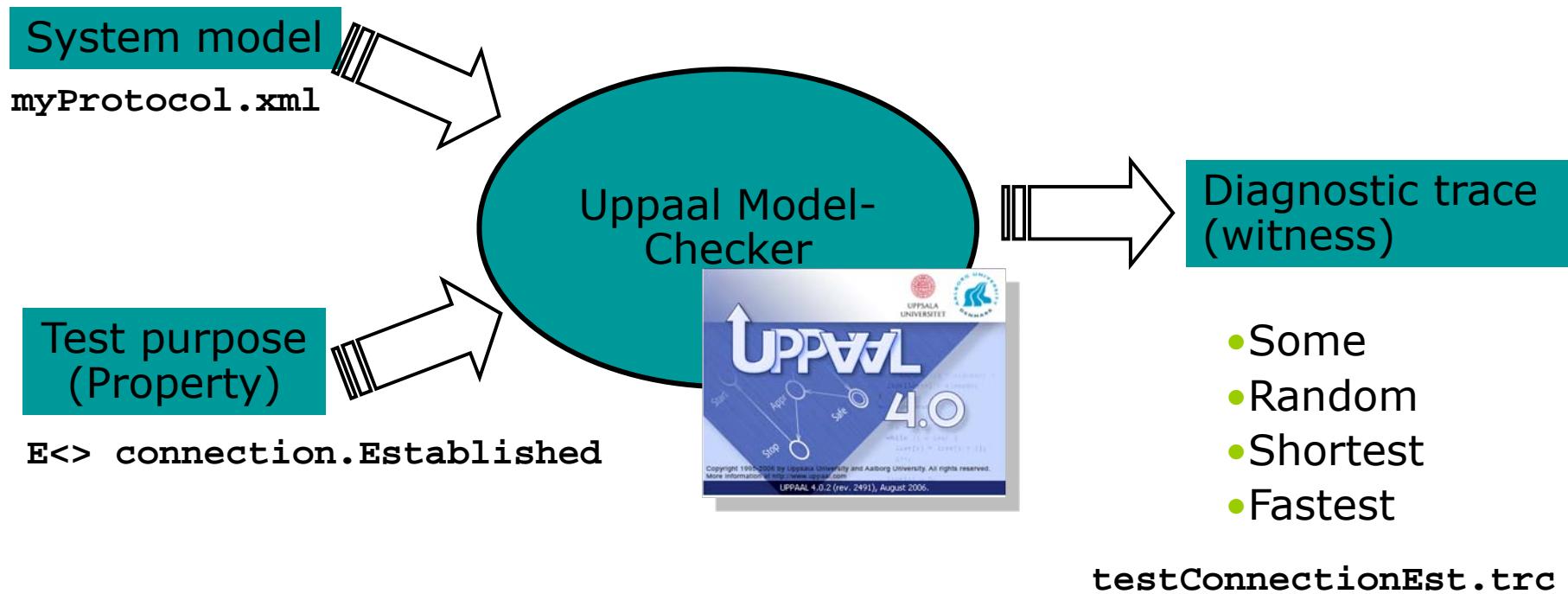


Infinitely many sequences!!!!!!

# Test Selection?

- Infinitely many sequences...
- But testing practice should definitely be finite
- To select finitely many out from an infinitely large pool
  - Test coverage criteria
  - Test purposes

# Test Generation by Model-Checking



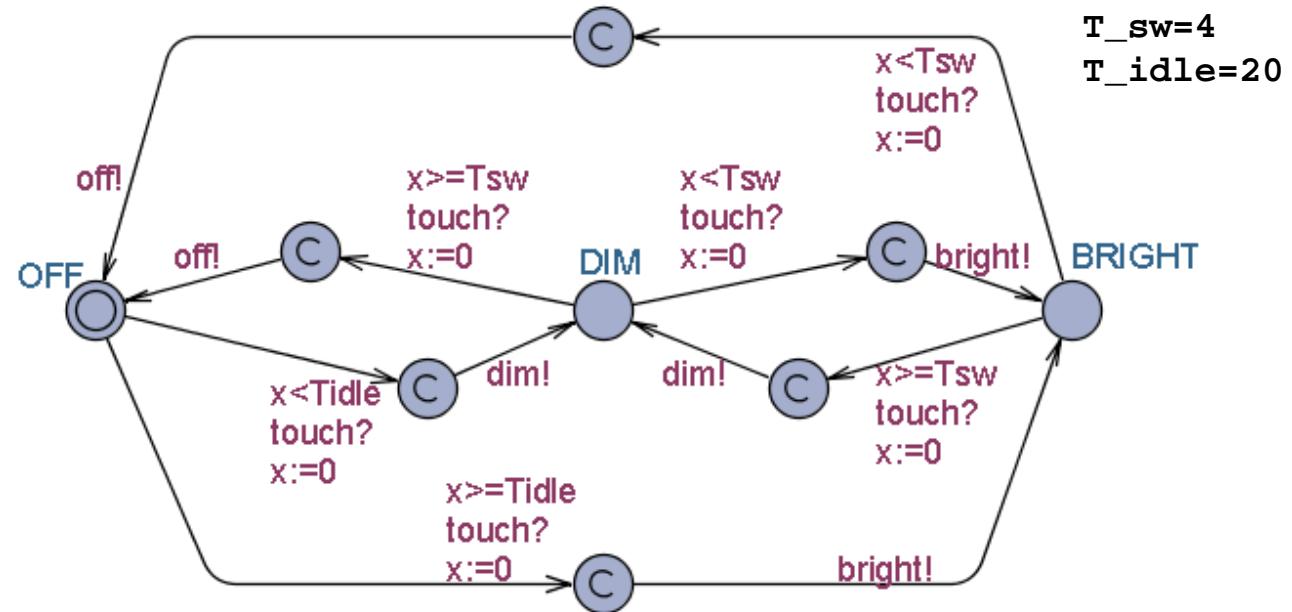
- Use diagnostic trace as test case??!!

# Controllable Timed Automata

- “**DOUTA**”-Model
  - Deterministic: two transitions with same input/output leads to the same state
  - Output-Urgent: enabled outputs will occur immediately
  - Isolated Outputs: if an output is enabled, no other output is enabled
  - Input-Enabled: all inputs can always be accepted

# A DOUTA Timed Automaton

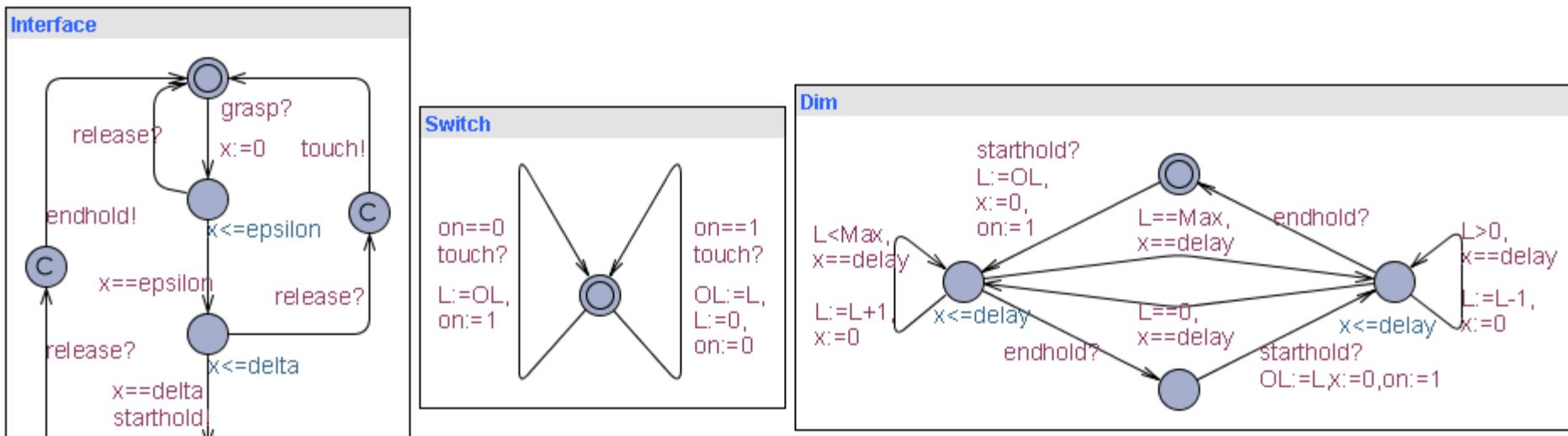
Deterministic,  
Output-Urgent,  
Isolated Outputs,  
Input-Enabled



**WANT:** if touch is issued twice quickly then the light will get brighter; otherwise the light is turned off.



# Without Test Purpose



## EXAMPLE test cases for Interface

- Epsilon=200ms
- Delta=500ms

0.grasp!·210.release!·touch?.PASS

0.grasp!·317.release!·touch?·2½.grasp!·220.release!·touch?.PASS

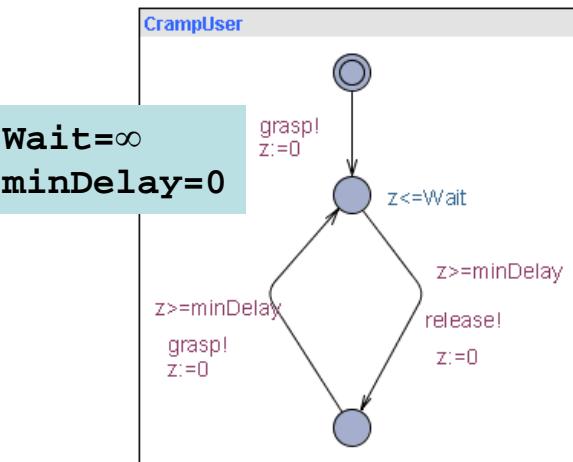
1000.grasp!·517.starthold?·100.release!·endhold?.PASS

Infinitely many sequences!!!!!!

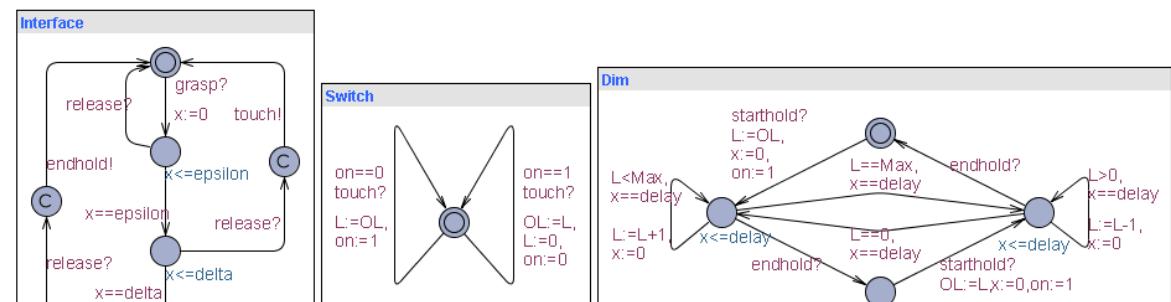
# Test Purpose #1

**Test Purpose:** A specific test objective (or observation) the tester wants to make on SUT

Environment model



System model



**TP1:** Check that the light can become bright:

**E <>> L == 1**

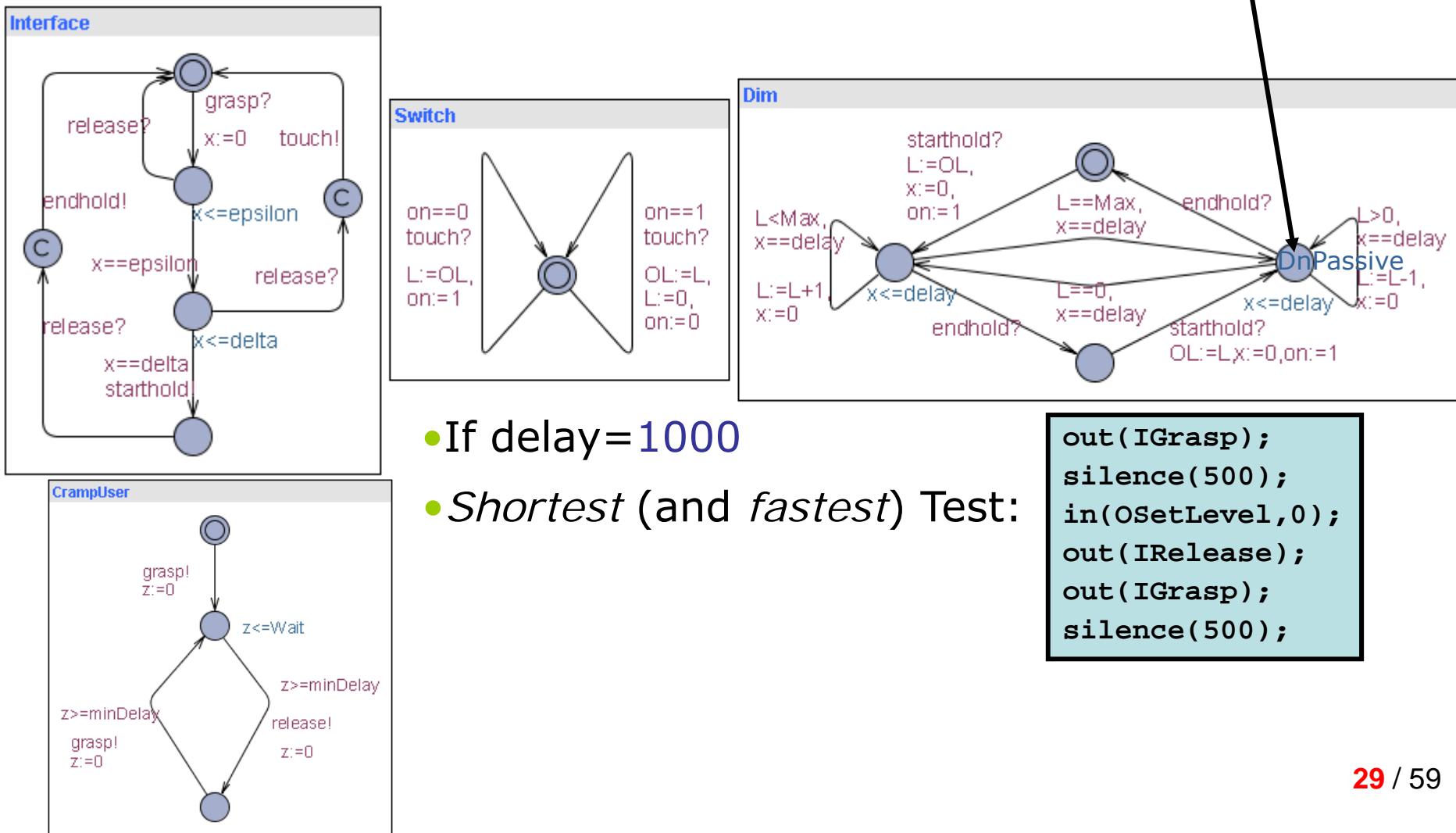
- *Shortest (and fastest) Test:*

```

out(IGrasp);silence(500);in(OSetLevel,0);silence(1000);
in(OSetLevel,1);silence(1000);in(OSetLevel,2); silence(1000);
in(OSetLevel,3);silence(1000);in(OSetLevel,4);silence(1000);
in(OSetLevel,5);silence(1000);in(OSetLevel,6);silence(1000);
in(OSetLevel,7);silence(1000);in(OSetLevel,8);silence(1000);
in(OSetLevel,9);silence(1000);in(OSetLevel,10);
out(IRelease);
  
```

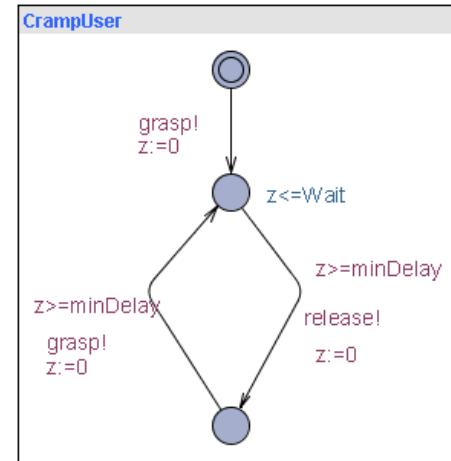
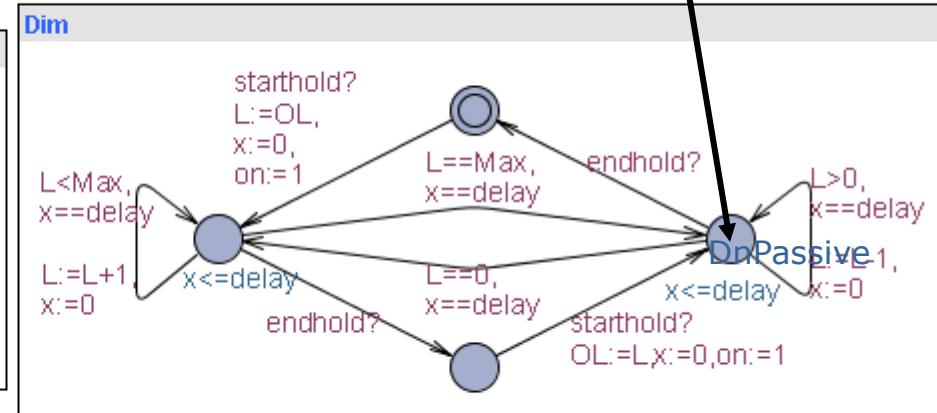
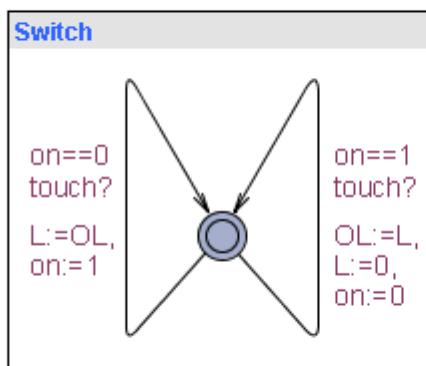
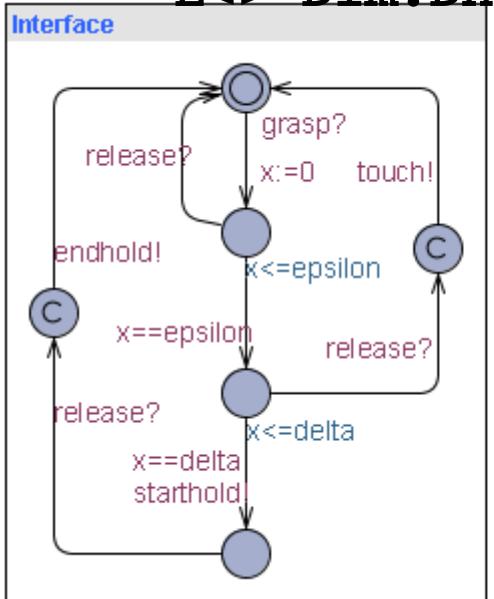
# Test Purpose #2

TP2: Check that controller can enter location 'DnPassive':  
**E<> Dim.DnPassive**



# Test Purpose #2

TP2: Check that controller can enter location 'DnPassive':  
**E<> Dim.DnPassive**



- If delay=40?
- Shortest Test:

```

out(IGrasp);
silence(500);
in(OSetLevel,0);
out(IRelase);
out(IGrasp);
silence(500);
  
```

- Fastest Test:

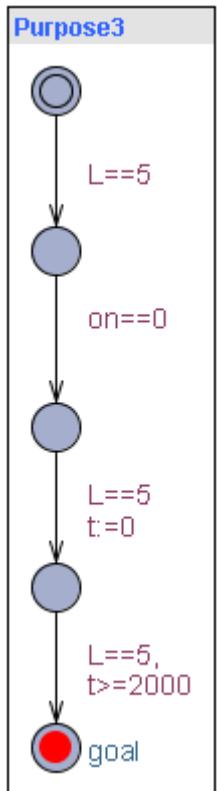
```

out(IGrasp);silence(500);in(OSetLevel,0);silence(40);
in(OSetLevel,1);silence(40);in(OSetLevel,2); silence(40);
in(OSetLevel,3);silence(40);in(OSetLevel,4); silence(40);
in(OSetLevel,5);silence(40);in(OSetLevel,6); silence(40);
in(OSetLevel,7);silence(40);in(OSetLevel,8); silence(40);
in(OSetLevel,9);silence(40);in(OSetLevel,10);silence(40);
  
```

# Test Purpose #3

TP3: Check that controller resets light level to previous value after switch-on.

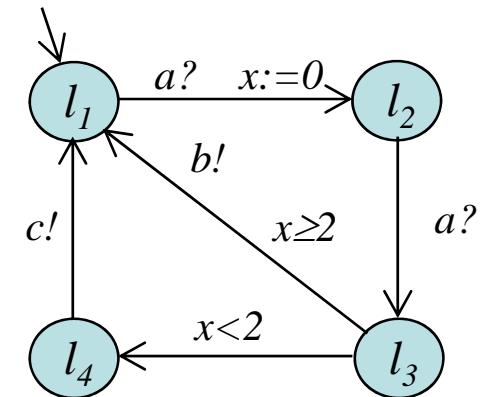
E<> Purpose3.goal



```
out(IGrasp); //set level to 5  
silence(500);  
in(OSetLevel,0);  
silence(1000);  
in(OSetLevel,1);  
silence(1000);  
in(OSetLevel,2);  
silence(1000);  
in(OSetLevel,3);  
silence(1000);  
in(OSetLevel,4);  
silence(1000);  
in(OSetLevel,5);  
out(IRelase);  
  
out(IGrasp); //touch To Off  
silence(200);  
out(IRelase);  
in(OSetLevel,0);  
  
out(IGrasp); //touch To On  
silence(200);  
out(IRelase);  
in(OSetLevel,5);  
  
silence(2000);
```

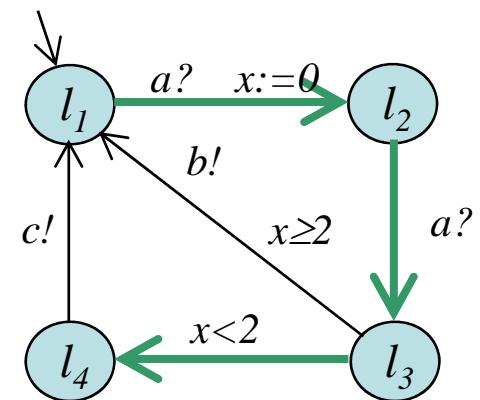
# Coverage-Based Test Generation

- Multi purpose testing
- Cover measurement
- Examples:
  - Location coverage,
  - Edge coverage,
  - Definition/use pair coverage



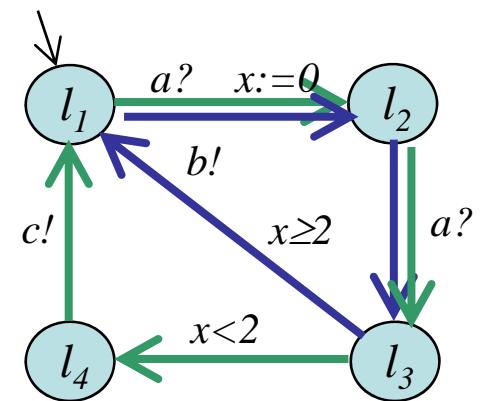
# Location Coverage

- Multi purpose testing
- Cover measurement
- Examples:
  - Location coverage,
  - Edge coverage,
  - Definition/use pair coverage



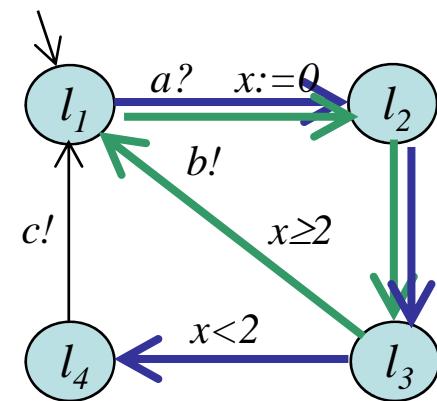
# Edge Coverage

- Multi purpose testing
- Cover measurement
- Examples:
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  - Edge coverage,
  - Definition/use pair coverage



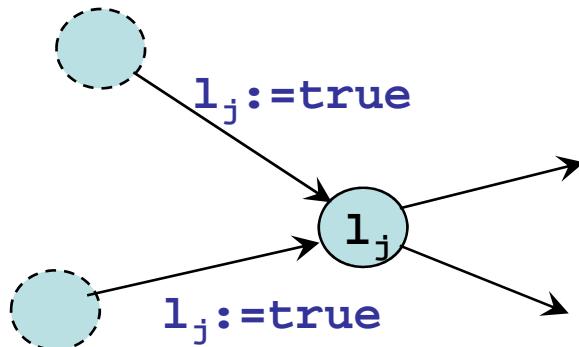
# Definition/Use Pair Coverage

- Multi purpose testing
- Cover measurement
- Examples:
  - Location Coverage,
  - Edge Coverage,
  - Definition/Use Pair Coverage



# Implementing Location Coverage

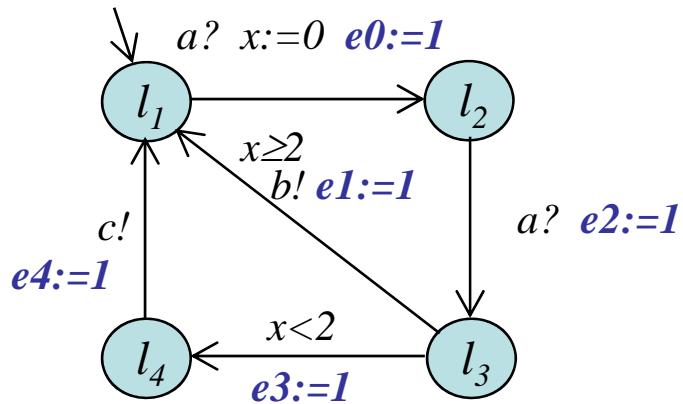
- Test sequence traversing all locations
- Encoding:
  - Enumerate locations  $l_0, \dots, l_n$
  - Add an auxiliary variable  $l_i$  for each location
  - Label each ingoing edge to location  $i$  with  $l_i := \text{true}$
  - Mark initial visited  $l_0 := \text{true}$
- Check:  $\mathbf{E} <> ( l_0 = \text{true} \wedge \dots \wedge l_n = \text{true} )$



UPPAAL CO $\check{V}$ ER

# Implementing Edge Coverage

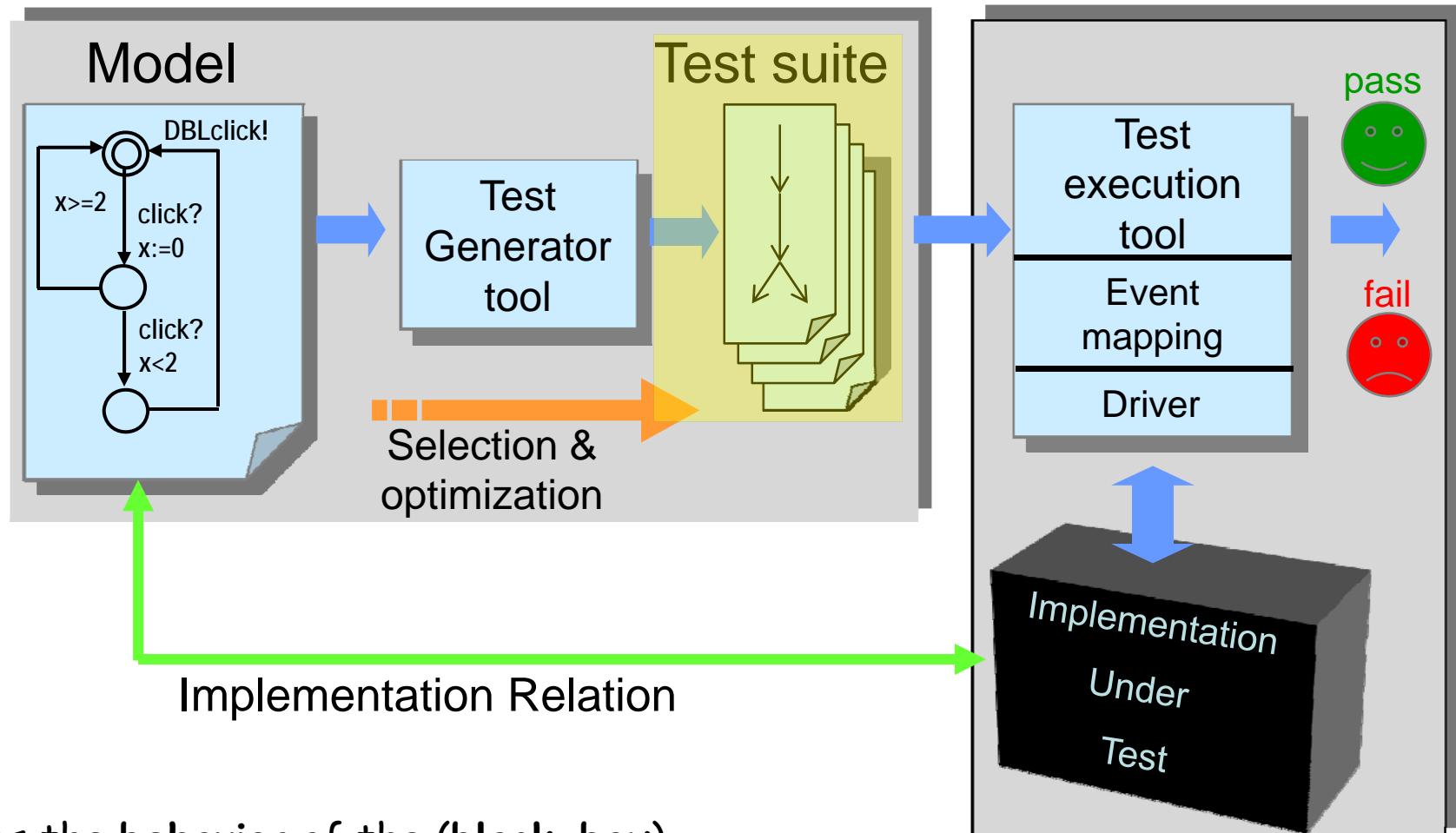
- Test sequence traversing all edges
- Encoding:
  - Enumerate edges  $e_0, \dots, e_n$
  - Add auxiliary variable  $e_i$  for each edge
  - Label each edge  $e_i := \text{true}$
- Check:  $\mathbf{E} <> ( e_0 = \text{true} \wedge \dots \wedge e_n = \text{true} )$



# Model-Based *On-line* Testing of Timed Systems

# Automated Model-Based Off-line Conformance testing

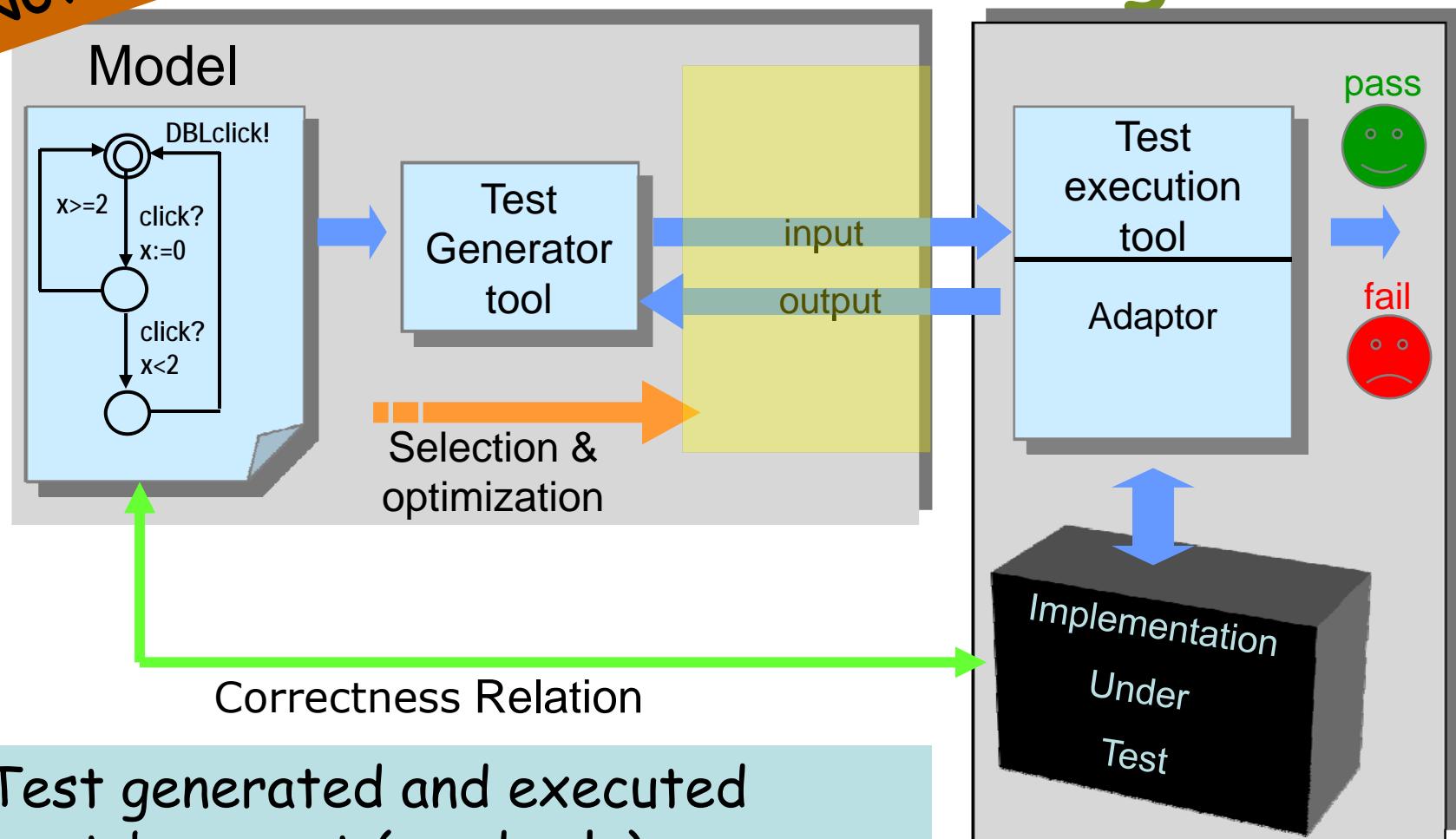
Recall...



Does the **behavior** of the (black-box)  
implementation **comply** to that of the specification?

# Automated Model-Based On-line Conformance testing

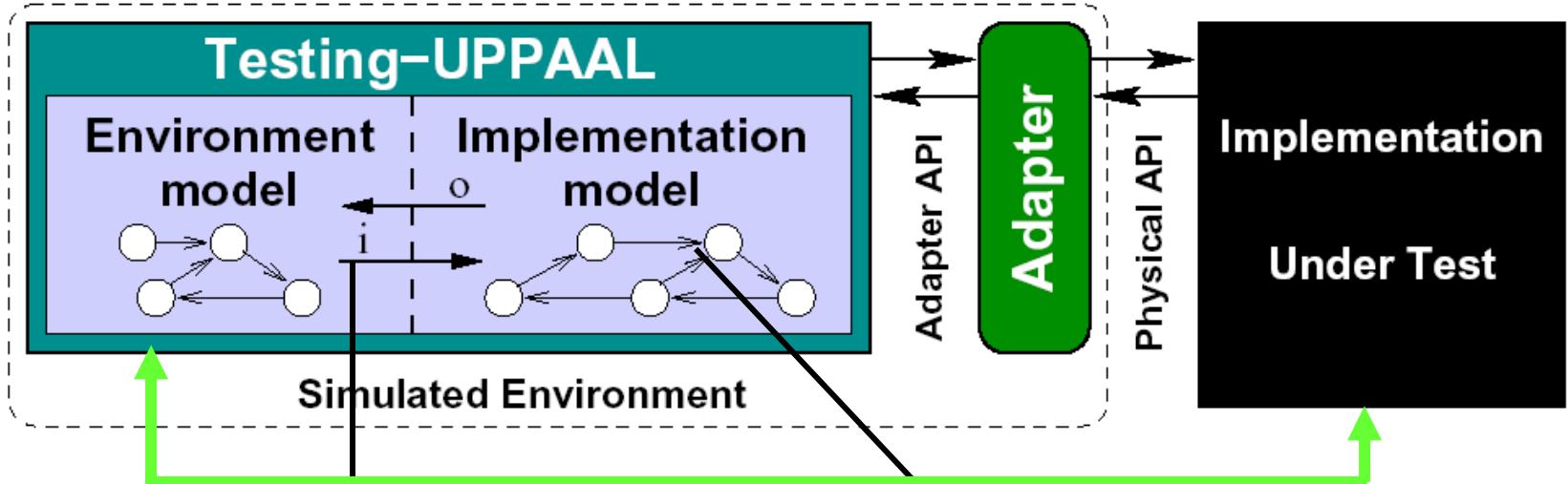
Now...



- Test generated and executed event-by-event (randomly)
- A.K.A. on-the-fly testing

# The Framework of Uppaal-TRON

- *UppAal Timed Automata Network: Env || IUT*



*"Relativized Timed i/o Conformance" Relation (rt-ioco)*

- Relevant input event sequences
- Load model

- Correct system behavior
- Test Oracle
- Monitor

- Complete and sound algorithm
- Efficient symbolic reachability algorithms
- **Uppaal-TRON**: Testing Real-time Systems **ONline**
- Release 1.4 <http://www.cs.aau.dk/~marius/tron/>

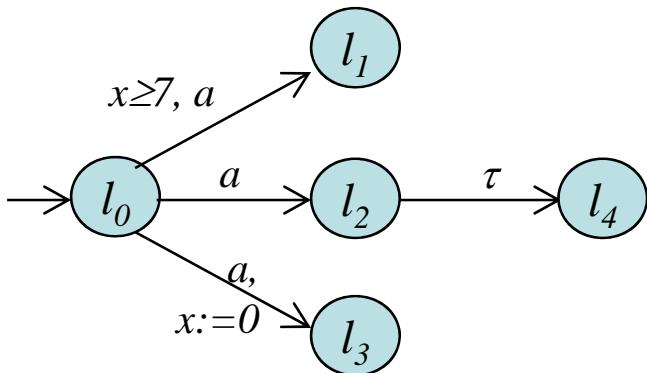
# On-line Testing

- Characteristica
  - very imaginative, "ingenious" tests sequences
  - long test sequences
  - stressful load
  - effective fault detection
- Tools exists but mostly NON-real-time
  - So-far systematic and explicit handling of real-time constraints missing

# State-set Computation

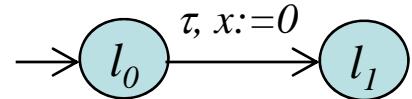
- Compute all potential states the model can occupy after the timed trace  $\varepsilon_0, i_0, \varepsilon_1, o_1, \varepsilon_2, i_2, o_2, \dots$
- Let  $Z$  be a set of states

**Z after a:** possible states after a (and  $\tau^*$ )



$\{ \langle l_0, x=3 \rangle \}$  after  $a =$   
 $\{ \langle l_2, x=3 \rangle, \langle l_4, x=3 \rangle, \langle l_3, x=0 \rangle \}$

**Z after ε:** possible states after  $\tau^*$  and  $\varepsilon_i$ , totaling a delay of  $\varepsilon$



$\{ \langle l_0, x=0 \rangle \}$  after 4 =  
 $\{ \langle l_0, x=4 \rangle, \langle l_1, 0 \leq x \leq 4 \rangle \}$

$$\langle l_0, x=0 \rangle \xrightarrow{1} \langle l_0, x=1 \rangle \xrightarrow{\tau} \langle l_1, x=0 \rangle \xrightarrow{3} \langle l_1, x=3 \rangle$$

# Algorithm Idea: State-set tracking

- Dynamically compute all potential states that the model  $M$  can reach after the timed trace  $\varepsilon_0, i_0, \varepsilon_1, o_1, \varepsilon_2, i_2, o_2, \dots$  [Tripakis] Failure Diagnosis
- $Z = M \text{ after } (\varepsilon_0, i_0, \varepsilon_1, o_1, \varepsilon_2, i_2, o_2)$
- If  $Z = \emptyset$  then IUT has made a computation not in model: **FAIL**
- $i$  is a relevant input in Env iff  $i \in \text{EnvOutput}(Z)$

# Uppaal-TRON On-line Testing Algorithm (skeleton)

**Algorithm** *TestGenExe* (*S, E, IUT, T*) **returns** {**pass**, **fail**}

$Z := \{(s_0, e_0)\}$ .

**while**  $Z \neq \emptyset \wedge \# \text{iterations} \leq T$  **do either** randomly:

1. // offer an input

**if** *EnvOutput*( $Z$ )  $\neq \emptyset$   
randomly choose  $i \in \text{EnvOutput}(Z)$   
**send**  $i$  to IUT  
 $Z := Z \text{ After } i$

2. // wait d for an output

randomly choose  $d \in \text{Delays}(Z)$   
**wait** (for  $d$  time units or output  $o$  at  $d' \leq d$ )  
**if**  $o$  occurred **then**

$Z := Z \text{ After } d'$

$Z := Z \text{ After } o$  // may become  $\emptyset$  ( $\Rightarrow$ fail)

**else**

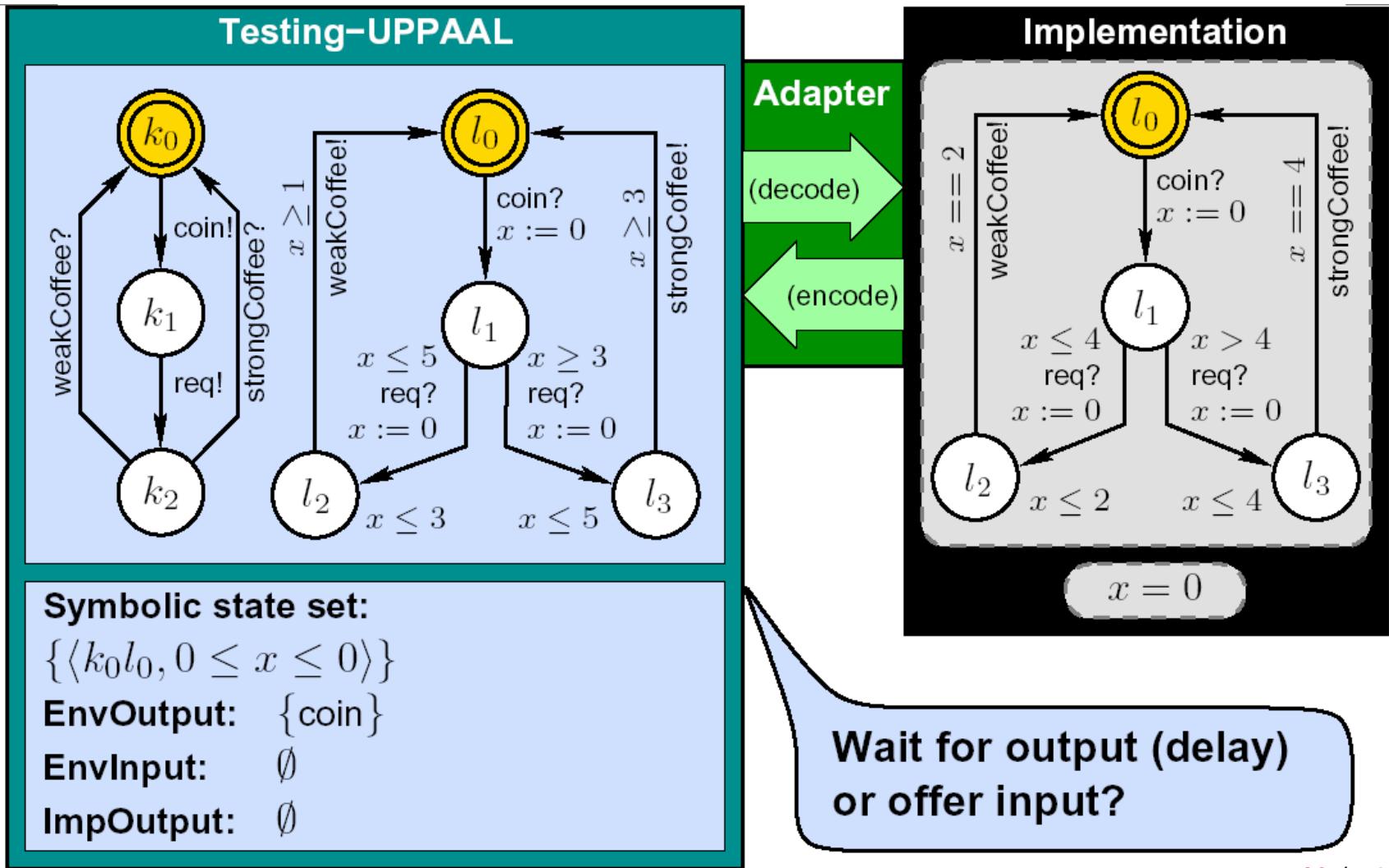
$Z := Z \text{ After } d$  // no output within  $d$  delay

3. restart:

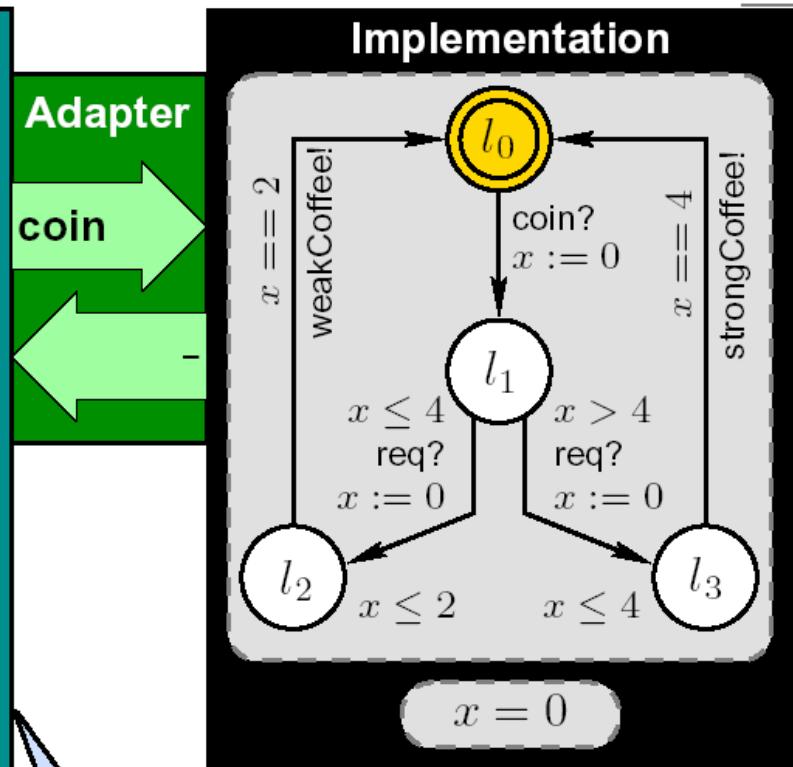
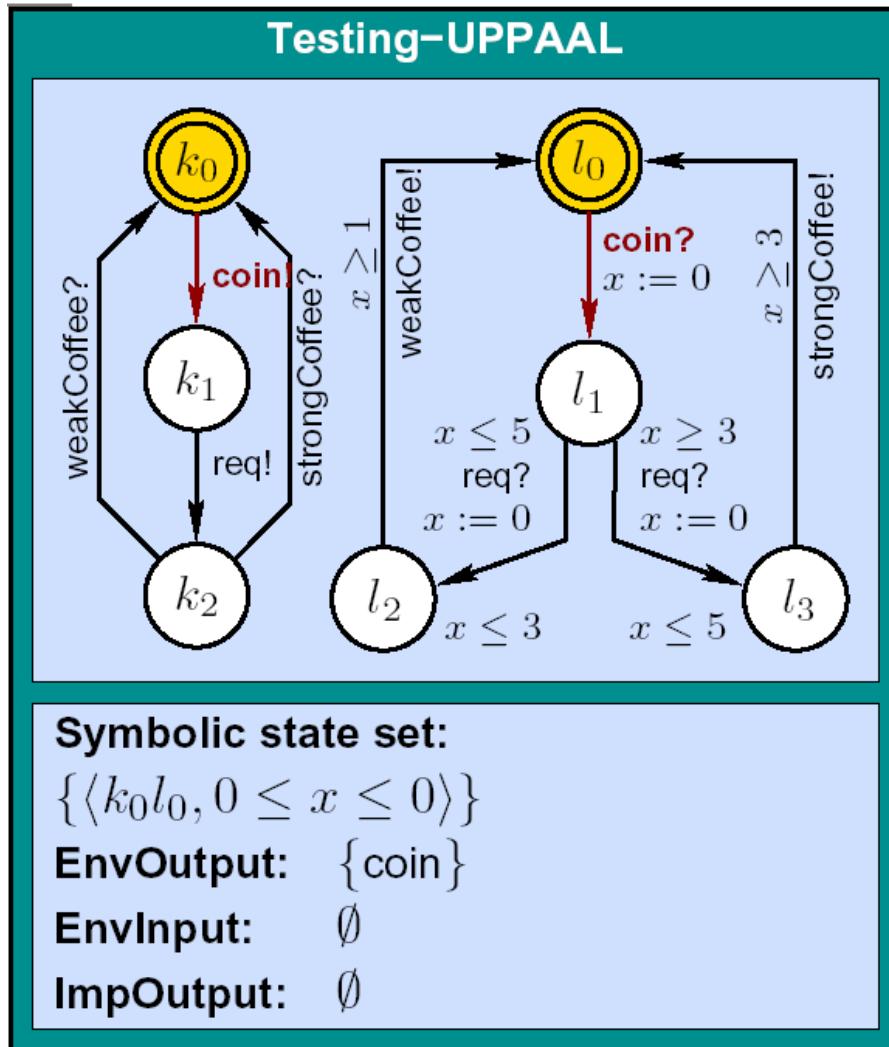
$Z := \{(s_0, e_0)\}$ , **reset** IUT //reset and restart

**if**  $Z = \emptyset$  **then return** **fail** **else return** **pass**

# On-line Testing Example (1)

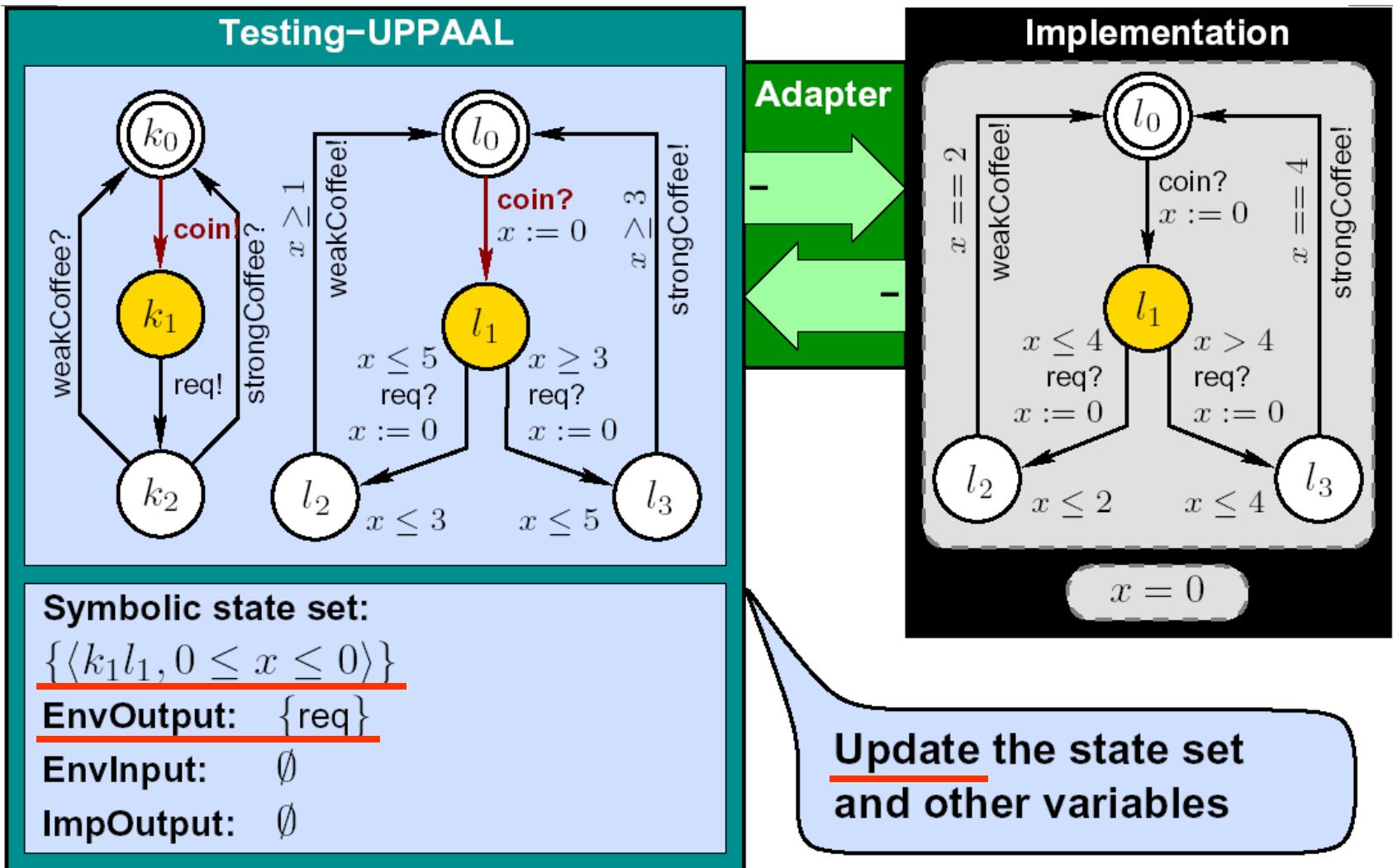


# On-line Testing Example (2)

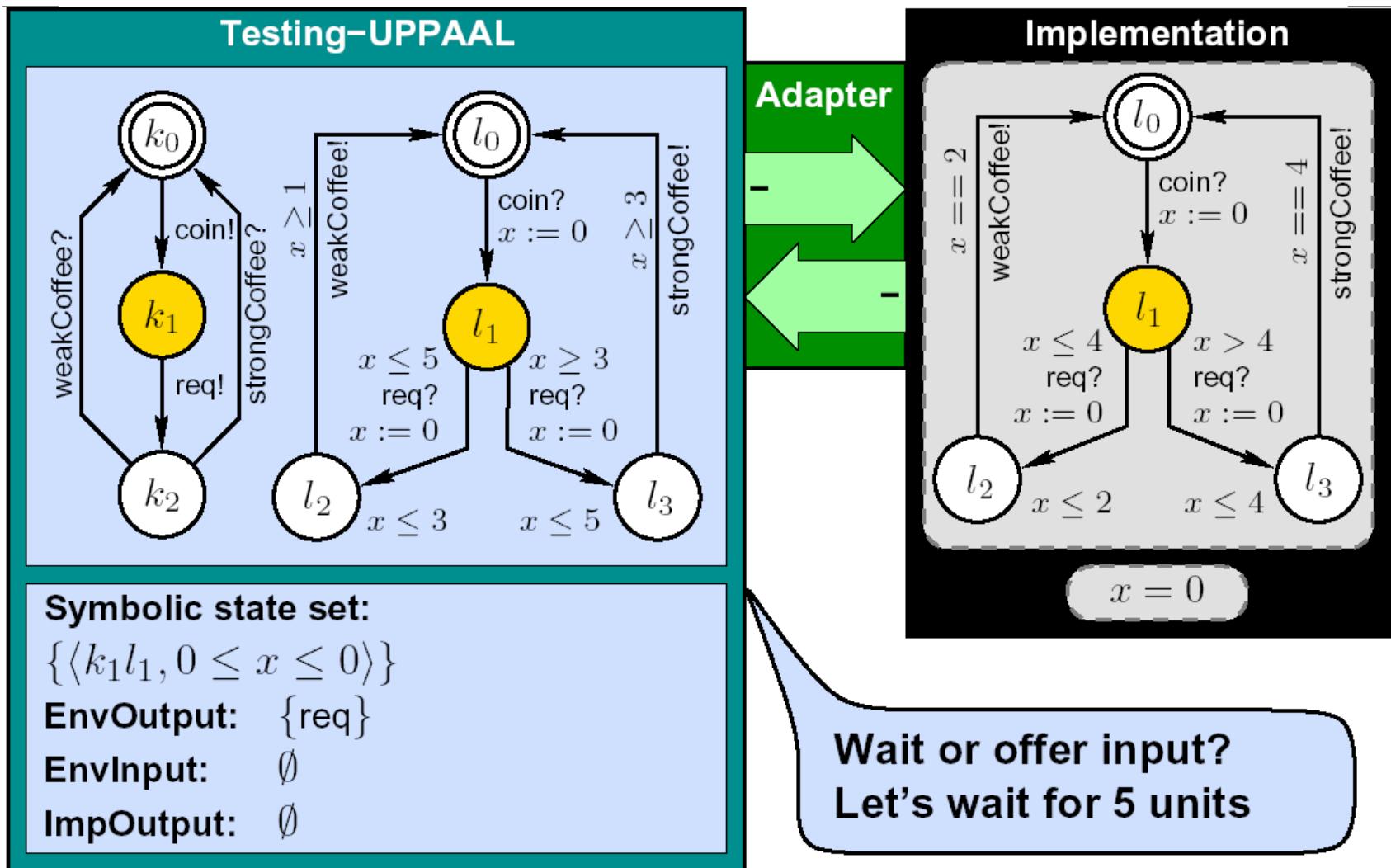


Let's offer input  
choose (the only) "coin"

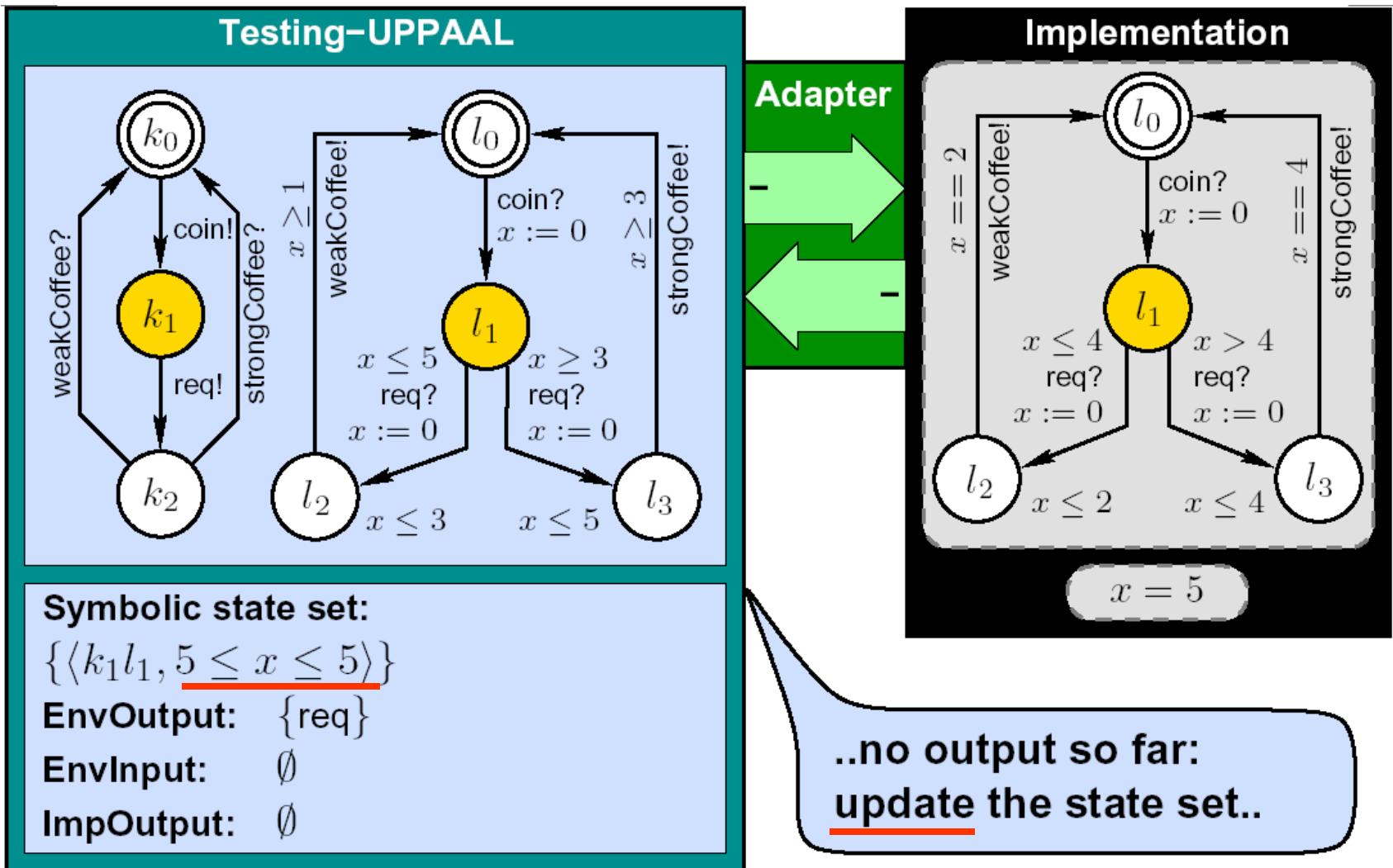
# On-line Testing Example (3)



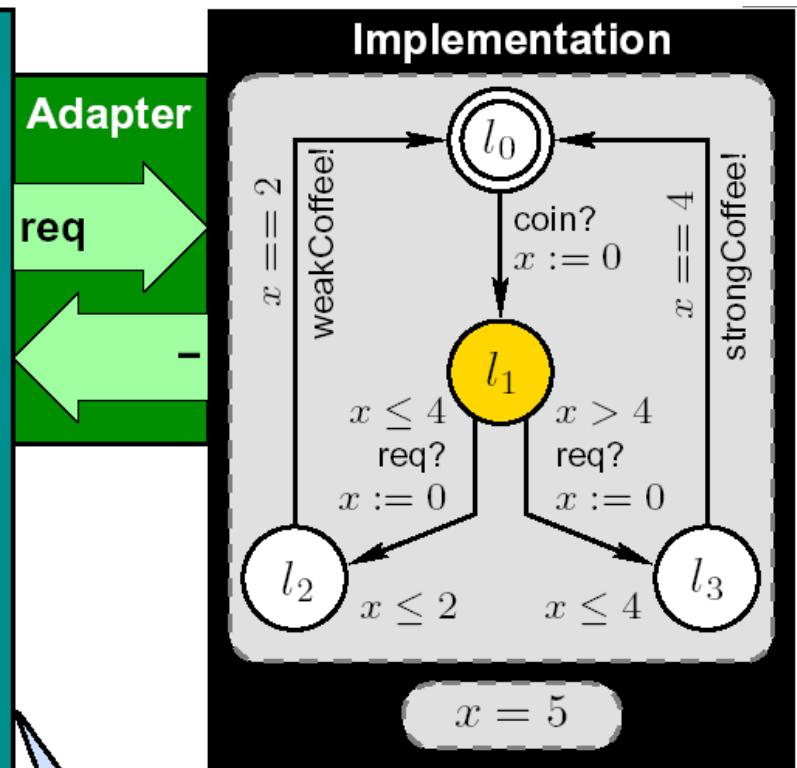
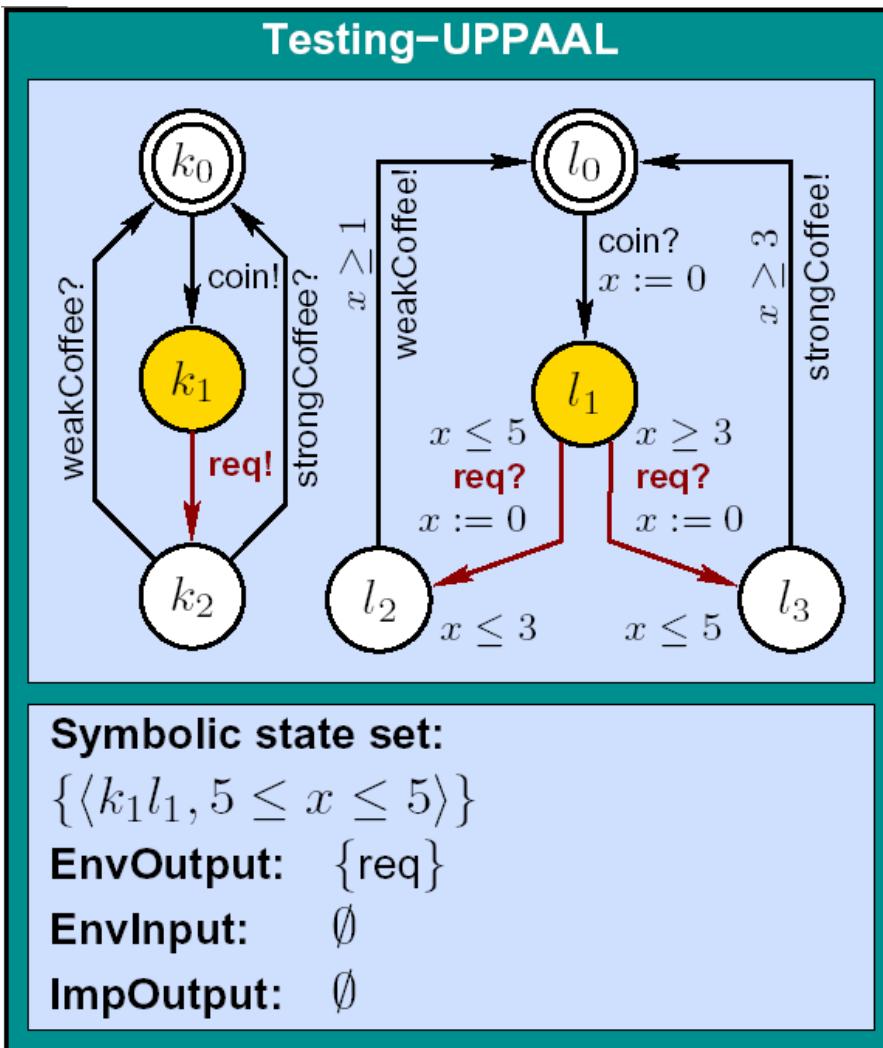
# On-line Testing Example (4)



# On-line Testing Example (5)

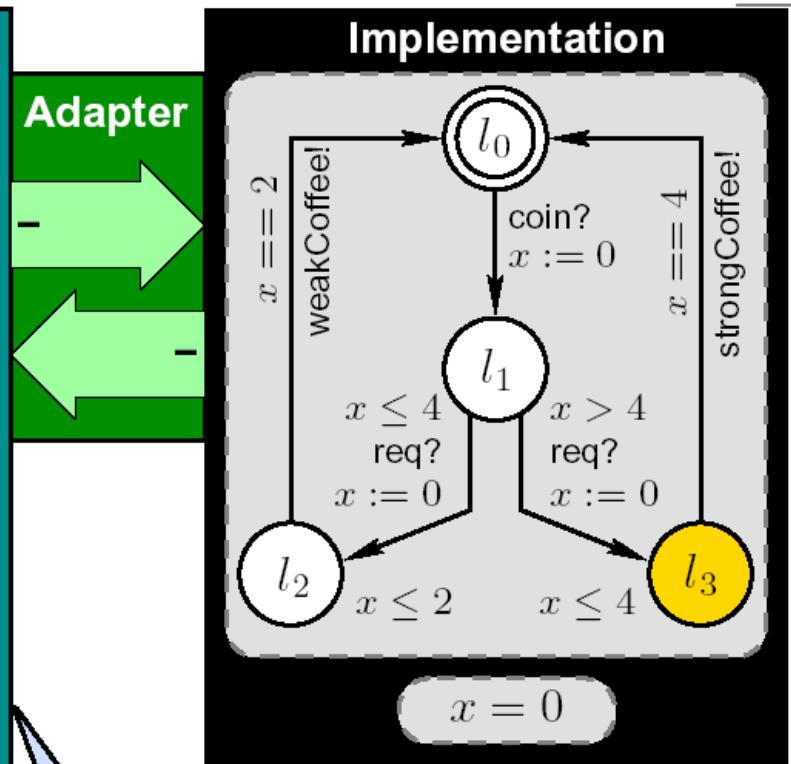
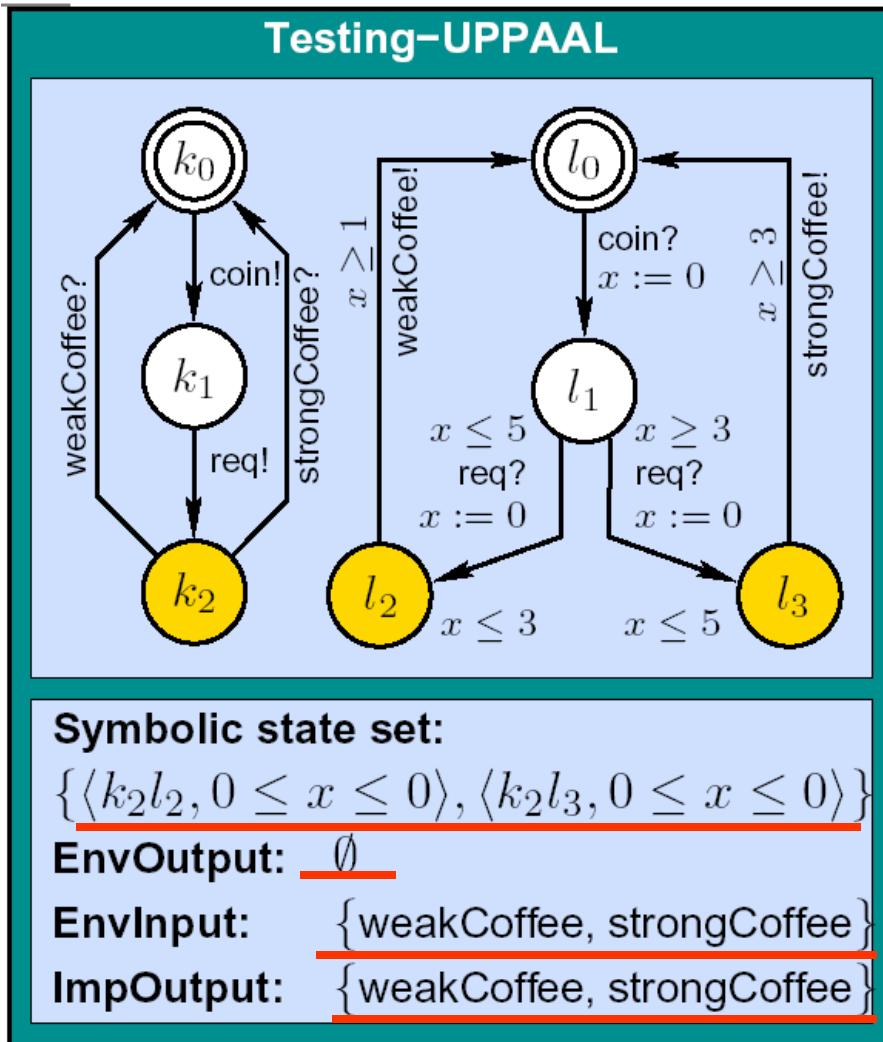


# On-line Testing Example (6)

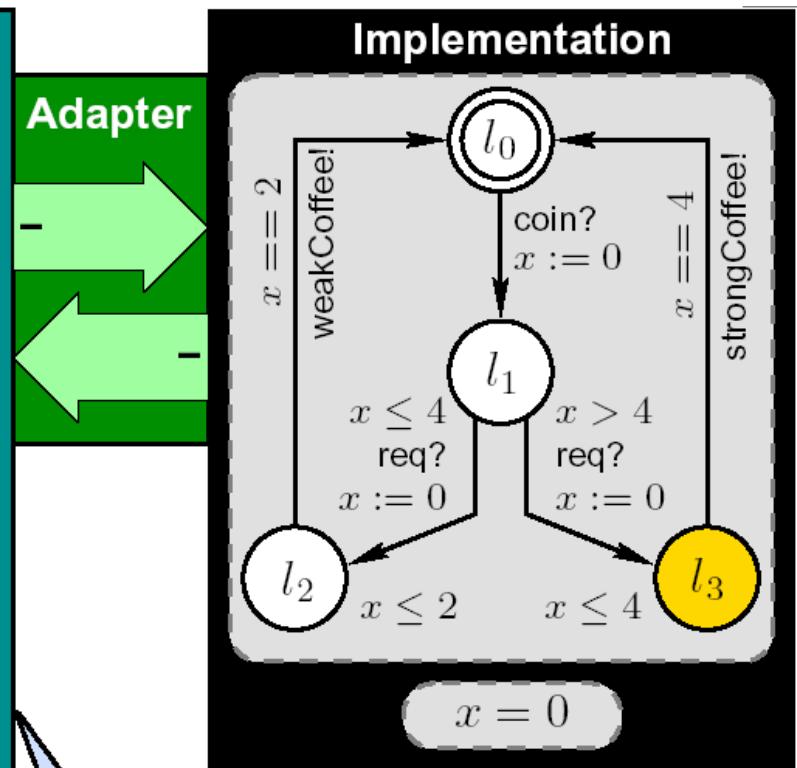
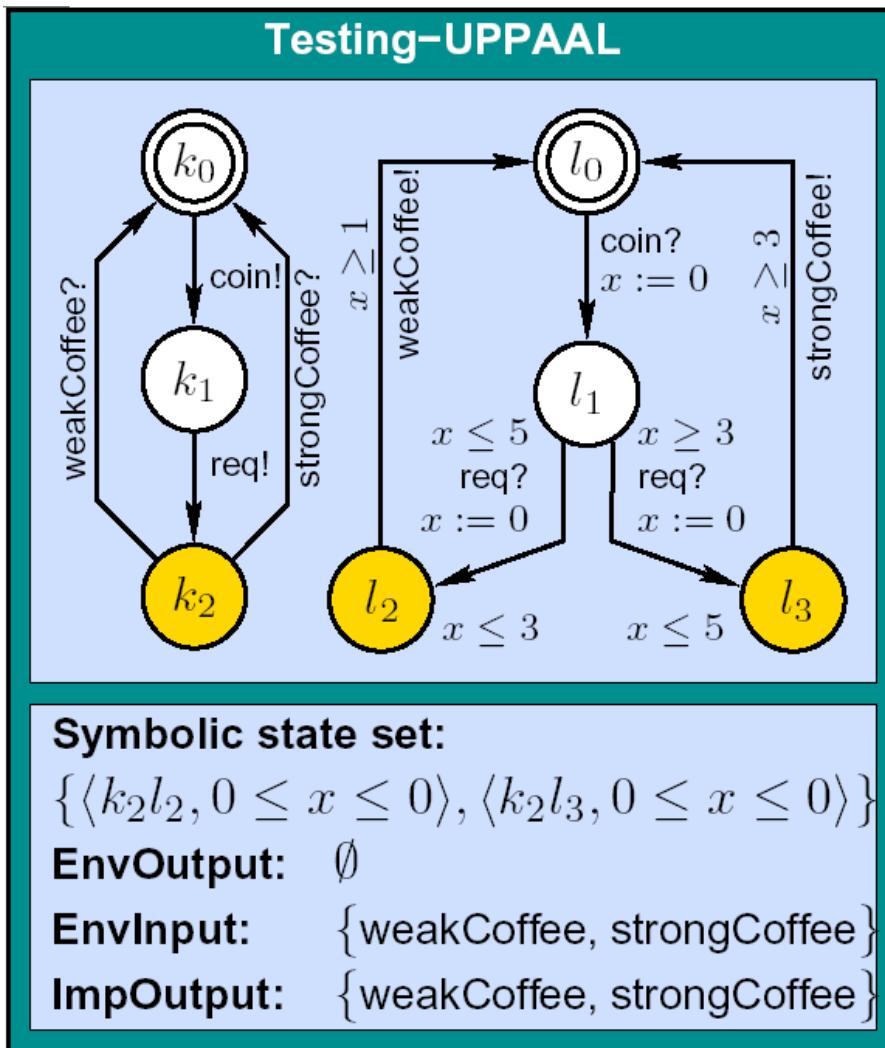


Wait or offer input?  
let's offer "req"

# On-line Testing Example (7)

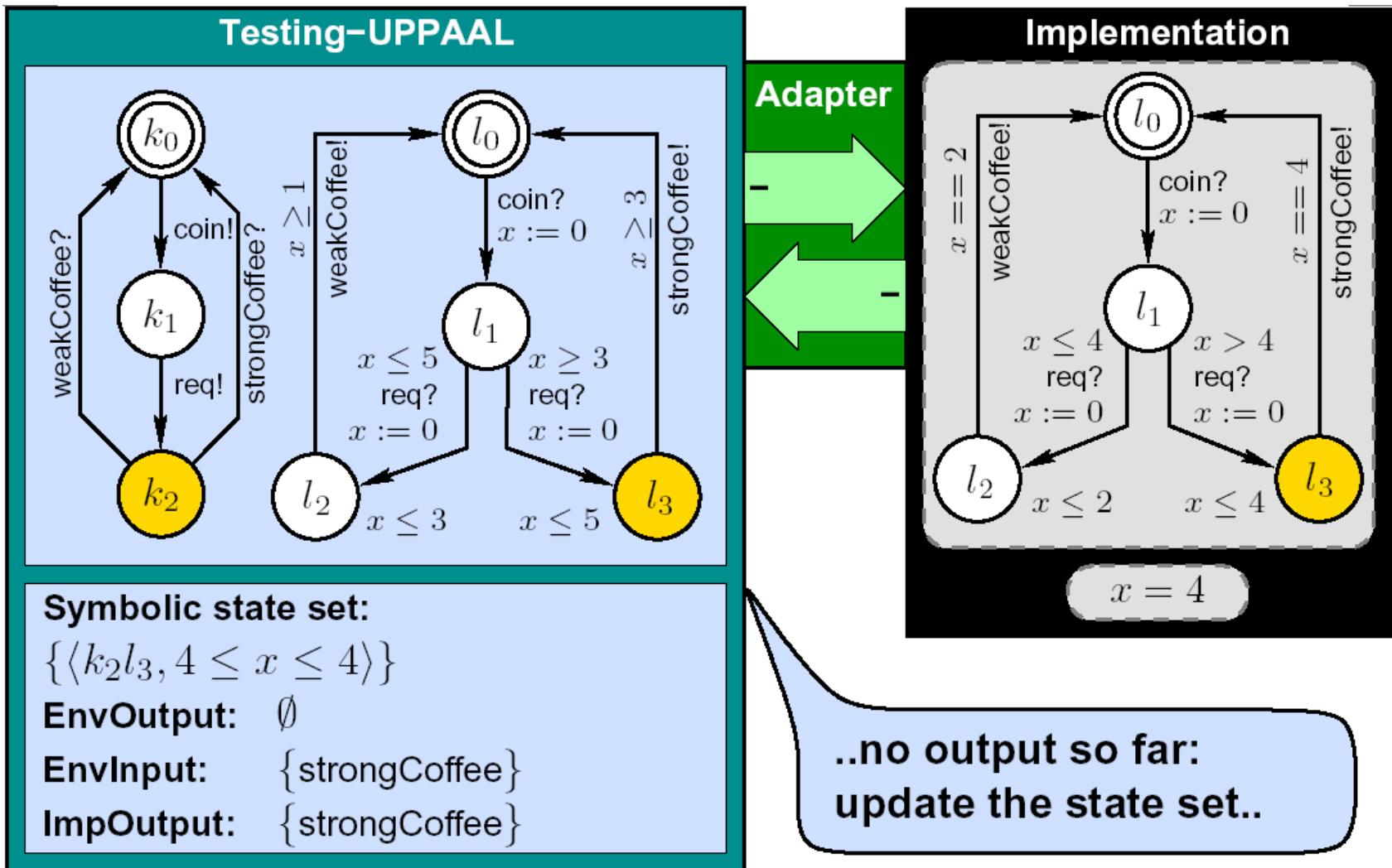


# On-line Testing Example (8)

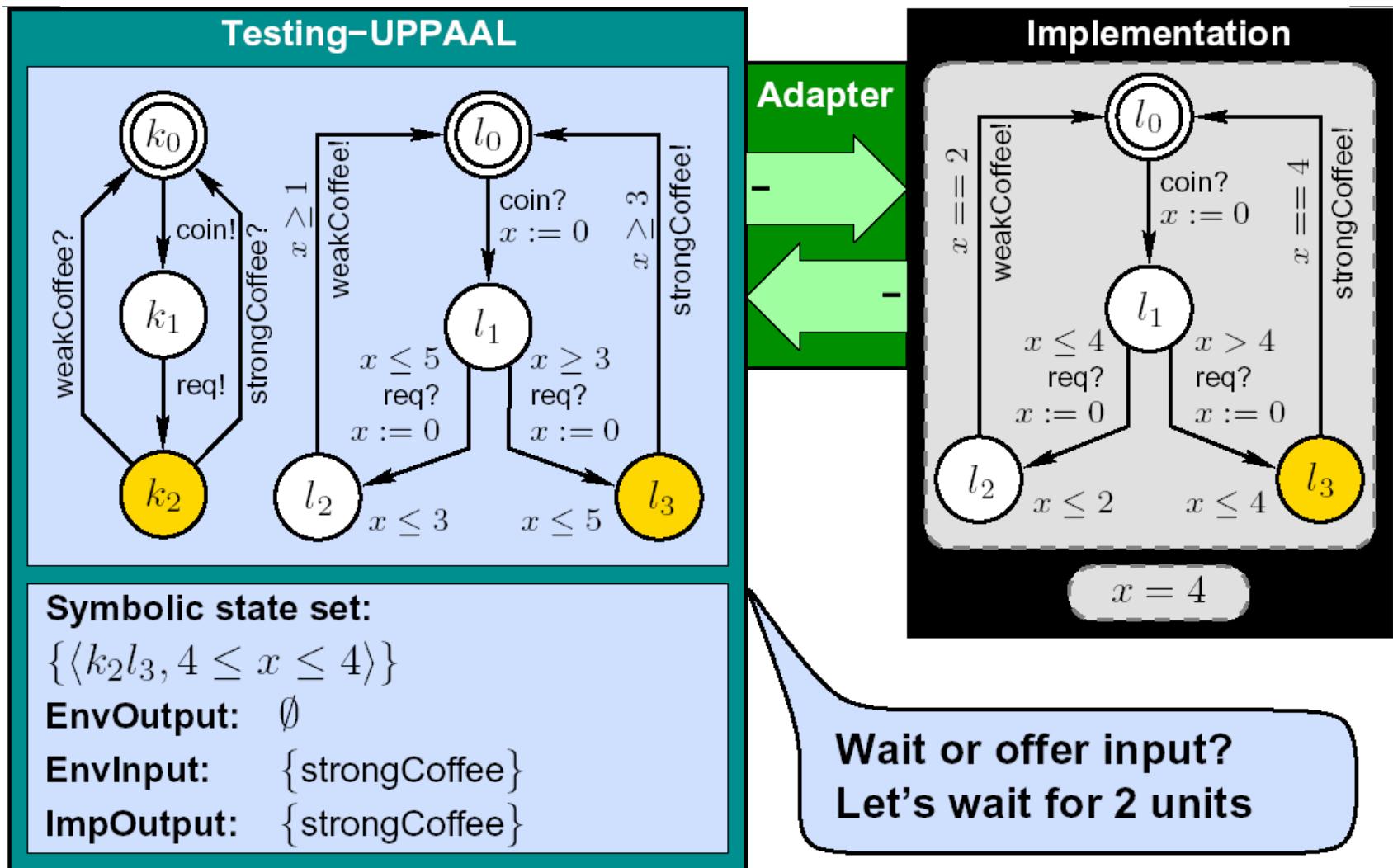


**Wait or offer input?  
Let's wait for 4 units**

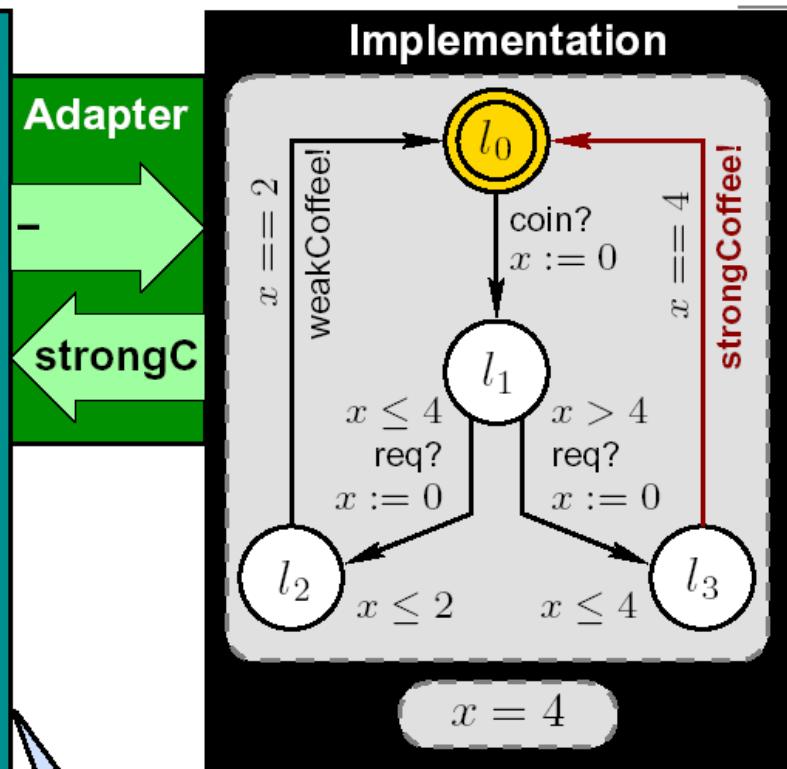
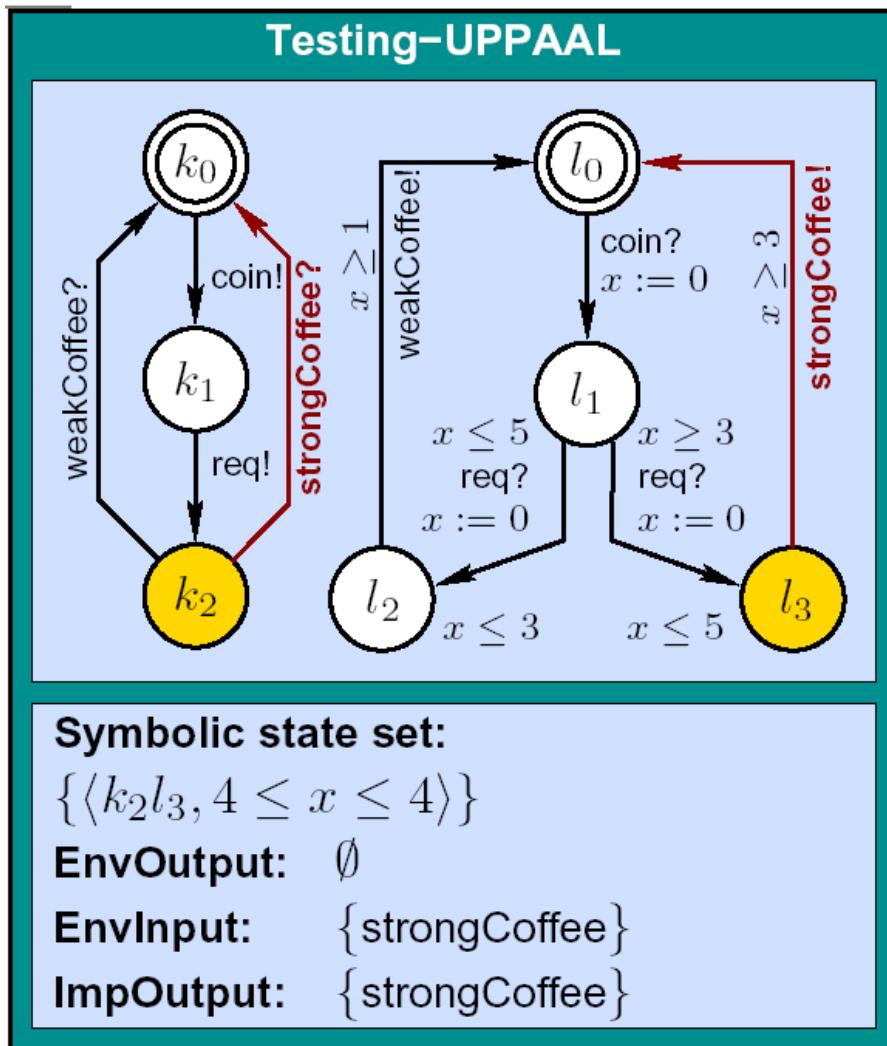
# On-line Testing Example (9)



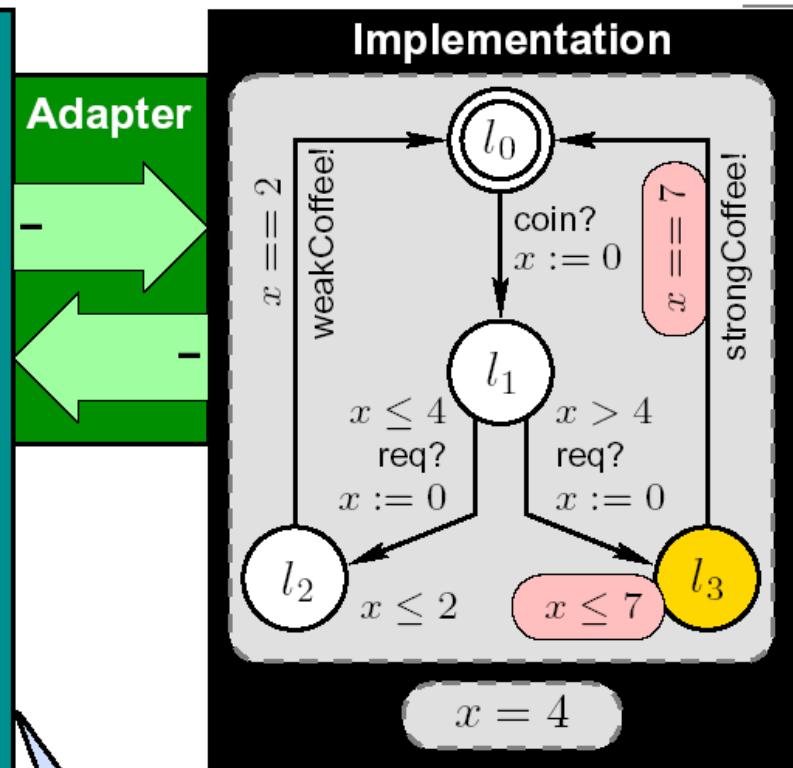
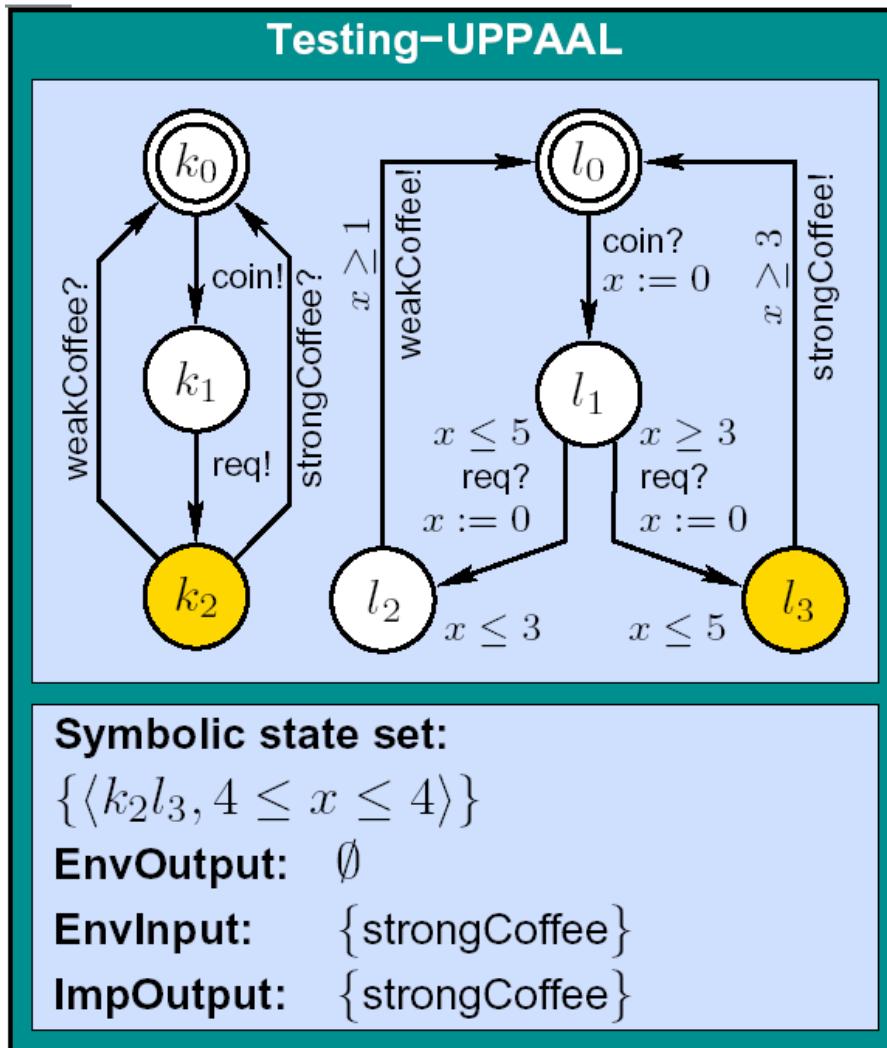
# On-line Testing Example (10)



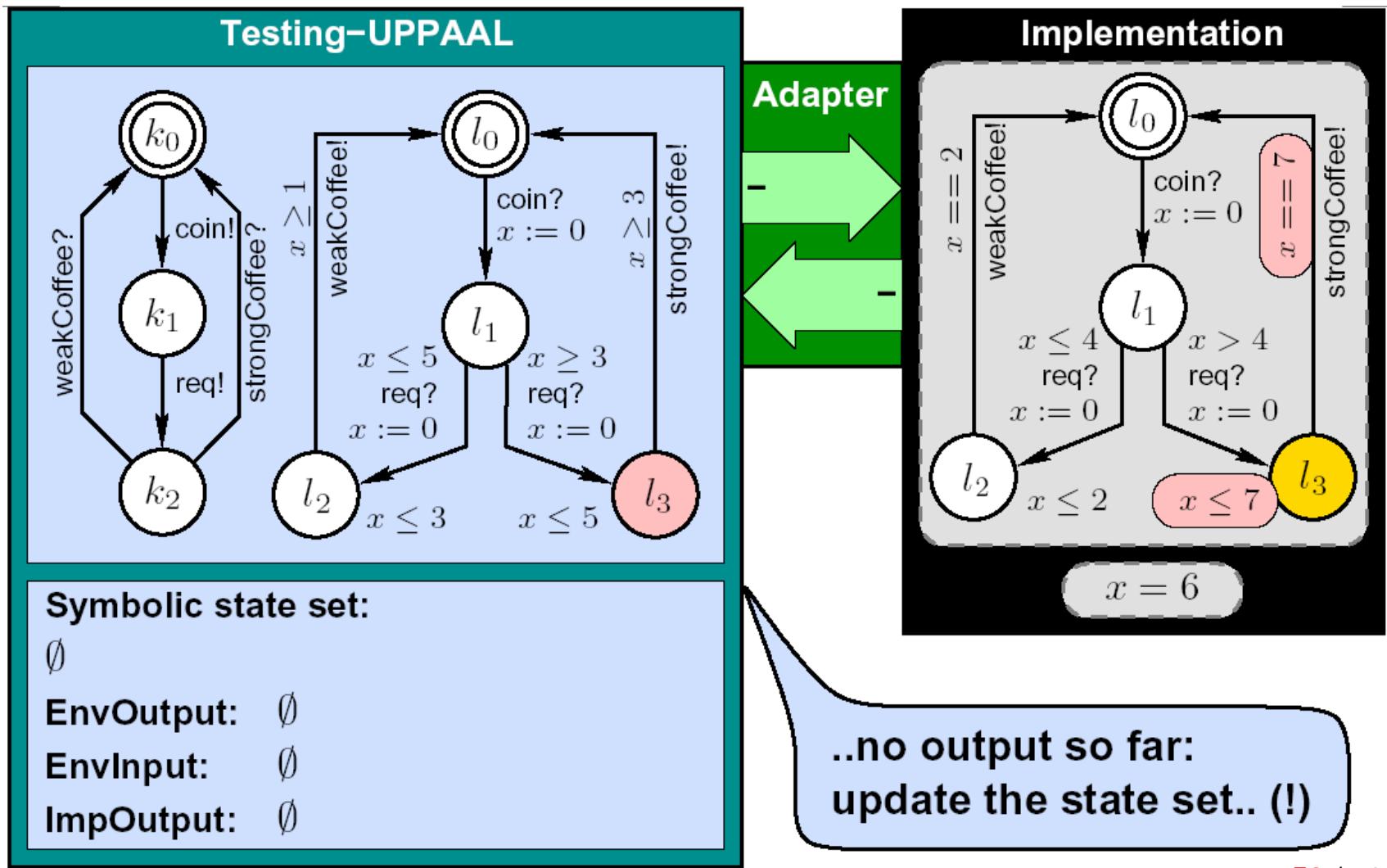
# On-line Testing Example (11)



# On-line Testing Example (12)



# On-line Testing Example (13)



# Further information

- Main Readings
  - Anders Hessel, Kim Guldstrand Larsen, Marius Mikucionis, Brian Nielsen, Paul Pettersson, and Arne Skou. "**Automated Model-Based Conformance Testing of Real-Time Systems**". In: Formal Methods and Testing, An Outcome of the FORTEST Network, Revised Selected Papers. Lecture Notes in Computer Science 4949 Springer 2008, pp.1-38.
- Industrial case studies
  - Anders Hessel, Paul Pettersson. "**Model-Based Testing of a WAP Gateway: An Industrial Case-Study**". FMICS/PDMC 2006: 116-131 (Uppaal-Cover)
  - Kim Guldstrand Larsen, Marius Mikucionis, Brian Nielsen, Arne Skou. "**Testing real-time embedded software using UPPAAL-TRON: an industrial case study**". EMSOFT 2005: 299-306 (Uppaal-TRON)